

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E6 instruction tests for VRR-i encoded:
				5 *
				6 * E650 VCVB - VECTOR CONVERT TO BINARY (32)
				7 * E652 VCVBG - VECTOR CONVERT TO BINARY (64)
				8 *
				9 * James Wekel June 2024
				10 *****
				11
				12 *****
				13 *
				14 * basic instruction tests
				15 *
				16 *****
				17 * This program tests proper functioning of the z/arch E6 VRR-i vector
				18 * convert to binary instructions. Exceptions are not tested.
				19 *
				20 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				21 * obvious coding errors. None of the tests are thorough. They are
				22 * NOT designed to test all aspects of any of the instructions.
				23 *
				24 *****
				25 *
				26 * *Testcase zvector-e6-11-convertbinary: VECTOR E6 VRR-i instruction
				27 * *
				28 * * Zvector E6 tests for VRR-i encoded instruction:
				29 * *
				30 * * E650 VCVB - VECTOR CONVERT TO BINARY (32)
				31 * * E652 VCVBG - VECTOR CONVERT TO BINARY (64)
				32 * *
				33 * * # -----
				34 * * # This tests only the basic function of the instruction.
				35 * * # Exceptions are NOT tested.
				36 * * # -----
				37 * *
				38 * main size 2
				39 * numcpu 1
				40 * sysclear
				41 * archlvl z/Arch
				42 *
				43 * diag8cmd enable # (needed for messages to Hercules console)
				44 * loadcore "\$(testpath)/zvector-e6-11-convertbinary.core" 0x0
				45 * diag8cmd disable # (reset back to default)
				46 *
				47 * *Done
				48 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				50 *****
				51 * FCHECK Macro - Is a Facility Bit set?
				52 *
				53 * If the facility bit is NOT set, an message is issued and
				54 * the test is skipped.
				55 *
				56 * Fcheck uses R0, R1 and R2
				57 *
				58 * eg. FCHECK 134, 'vector-packed-decimal'
				59 *****
				60 MACRO
				61 FCHECK &BITNO, &NOTSETMSG
				62 . * &BITNO : facility bit number to check
				63 . * &NOTSETMSG : 'facility name'
				64 LCLA &FBBYTE Facility bit in Byte
				65 LCLA &FBBIT Facility bit within Byte
				66
				67 LCLA &L(8)
				68 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte
				69
				70 &FBBYTE SETA &BITNO/8
				71 &FBBIT SETA &L((&BITNO-(&FBBYTE*8))+1)
				72 . * MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
				73
				74 B X&SYSNDX
				75 * Fcheck data area
				76 * skip messgae
				77 SKT&SYSNDX DC C' Skipping tests: '
				78 DC C&NOTSETMSG
				79 DC C' facility (bit &BITNO) is not installed.'
				80 SKL&SYSNDX EQU *-SKT&SYSNDX
				81 * facility bits
				82 DS FD gap
				83 FB&SYSNDX DS 4FD
				84 DS FD gap
				85 *
				86 X&SYSNDX EQU *
				87 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1
				88 STFLE FB&SYSNDX get facility bits
				89
				90 XGR R0, R0
				91 IC R0, FB&SYSNDX+&FBBYTE get fbit byte
				92 N R0, =F' &FBBIT' is bit set?
				93 BNZ XC&SYSNDX
				94 *
				95 * facility bit not set, issue message and exit
				96 *
				97 LA R0, SKL&SYSNDX message length
				98 LA R1, SKT&SYSNDX message address
				99 BAL R2, MSG
				100
				101 B EOJ
				102 XC&SYSNDX EQU *
				103 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				125 *****
				126 * The actual "ZVE6TST" program itself...
				127 *****
				128 *
				129 * Architecture Mode: z/Arch
				130 * Register Usage:
				131 *
				132 * R0 (work)
				133 * R1-4 (work)
				134 * R5 Testing control table - current test base
				135 * R6- R7 (work)
				136 * R8 First base register
				137 * R9 Second base register
				138 * R10 Third base register
				139 * R11 E6TEST call return
				140 * R12 E6TESTS register
				141 * R13 (work)
				142 * R14 Subroutine call
				143 * R15 Secondary Subroutine call or work
				144 *
				145 *****
00000200		00000200		147 USING BEGIN, R8 FIRST Base Register
00000200		00001200		148 USING BEGIN+4096, R9 SECOND Base Register
00000200		00002200		149 USING BEGIN+8192, R10 THIRD Base Register
				150
00000200	0580			151 BEGIN BALR R8, 0 Initalize FIRST base register
00000202	0680			152 BCTR R8, 0 Initalize FIRST base register
00000204	0680			153 BCTR R8, 0 Initalize FIRST base register
				154
00000206	4190 8800		00000800	155 LA R9, 2048(, R8) Initalize SECOND base register
0000020A	4190 9800		00000800	156 LA R9, 2048(, R9) Initalize SECOND base register
				157
0000020E	41A0 9800		00000800	158 LA R10, 2048(, R9) Initalize THIRD base register
00000212	41A0 A800		00000800	159 LA R10, 2048(, R10) Initalize THIRD base register
				160
00000216	B600 8334		00000534	161 STCTL R0, R0, CTLR0 Store CRO to enable AFP
0000021A	9604 8335		00000535	162 OI CTLR0+1, X' 04' Turn on AFP bit
0000021E	9602 8335		00000535	163 OI CTLR0+1, X' 02' Turn on Vector bit
00000222	B700 8334		00000534	164 LCTL R0, R0, CTLR0 Reload updated CRO
				165
				166 *****
				167 * Is Vector packed-decimal facility installed (bit 134)
				168 *****
				169
00000226	47F0 80B0		000002B0	170 FCHECK 134, ' vector-packed- decimal '
				171+ B X0001
				172+ * Fcheck data area
				173+ * skip messgae
0000022A	40404040 40404040			174+SKT0001 DC C' Skipping tests: '
00000244	A58583A3 96996097			175+ DC C' vector-packed-decimal '
00000259	40868183 899389A3			176+ DC C' facility (bit 134) is not installed. '
		00000054 00000001		177+SKL0001 EQU *- SKT0001
				178+ * facility bits
00000280	00000000 00000000			179+ DS FD gap
00000288	00000000 00000000			180+FB0001 DS 4FD

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						235	*****
						236	* cc was not as expected
						237	*****
00000322	E310	0001	0082	00000322	00000001	238	CCMSG EQU *
00000328	E310	5007	0076		00000001	239	XG R1, R1
0000032E	5410	8344			00000007	240	LB R1, M3 m3 has CS bit
00000332	4780	8106			00000544	241	N R1, =F' 1' get CS (CC set) bit
					00000306	242	BZ TESTREST ignore if not set
						243	*
						244	* extract CC extracted PSW
						245	*
00000336	5810	8ED8			000010D8	246	L R1, CCPSW
0000033A	8810	000C			0000000C	247	SRL R1, 12
0000033E	5410	8348			00000548	248	N R1, =XL4' 3'
00000342	4210	8EE0			000010E0	249	STC R1, CCFOUND save cc
						250	*
						251	* FILL IN MESSAGE
						252	*
00000346	4820	5004			00000004	253	LH R2, TNUM get test number and convert
0000034A	4E20	8EC8			000010C8	254	CVD R2, DECNUM
0000034E	D211	8EB2	8E9C	000010B2	0000109C	255	MVC PRT3, EDIT
00000354	DE11	8EB2	8EC8	000010B2	000010C8	256	ED PRT3, DECNUM
0000035A	D202	8E57	8EBF	00001057	000010BF	257	MVC CCPRTNUM(3), PRT3+13 fill in message with test #
						258	
00000360	D207	8E74	500A	00001074	0000000A	259	MVC CCPRTNAME, OPNAME fill in message with instruction
						260	
00000366	B982	0022				261	XGR R2, R2 get CC as U8
0000036A	4320	5008			00000008	262	IC R2, CC
0000036E	4E20	8EC8			000010C8	263	CVD R2, DECNUM and convert
00000372	D211	8EB2	8E9C	000010B2	0000109C	264	MVC PRT3, EDIT
00000378	DE11	8EB2	8EC8	000010B2	000010C8	265	ED PRT3, DECNUM
0000037E	D200	8E8A	8EC1	0000108A	000010C1	266	MVC CCPRTEXP(1), PRT3+15 fill in message with CC field
						267	
00000384	B982	0022				268	XGR R2, R2 get CCFOUND as U8
00000388	4320	8EE0			000010E0	269	IC R2, CCFOUND
0000038C	4E20	8EC8			000010C8	270	CVD R2, DECNUM and convert
00000390	D211	8EB2	8E9C	000010B2	0000109C	271	MVC PRT3, EDIT
00000396	DE11	8EB2	8EC8	000010B2	000010C8	272	ED PRT3, DECNUM
0000039C	D200	8E9A	8EC1	0000109A	000010C1	273	MVC CCPRTGOT(1), PRT3+15 fill in message with ccfound
						274	
000003A2	4100	0055			00000055	275	LA R0, CCPRTLNG message length
000003A6	4110	8E47			00001047	276	LA R1, CCPRTLNE messagfe address
000003AA	45F0	821A			0000041A	277	BAL R15, RPTERROR
						278	
000003AE	47F0	81FC			000003FC	279	B FAILCONT

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						281 *****	
						282 * result not as expected:	
						283 * issue message with test number, instruction under test	
						284 * and instruction l2	
						285 *****	
				000003B2	00000001	286 FAILMSG EQU *	
000003B2	4820	5004			00000004	287 LH R2, TNUM	get test number and convert
000003B6	4E20	8EC8			000010C8	288 CVD R2, DECNUM	
000003BA	D211	8EB2 8E9C		000010B2	0000109C	289 MWC PRT3, EDIT	
000003C0	DE11	8EB2 8EC8		000010B2	000010C8	290 ED PRT3, DECNUM	
000003C6	D202	8E18 8EBF		00001018	000010BF	291 MWC PRTNUM(3), PRT3+13	fill in message with test #
						292	
000003CC	D207	8E33 500A		00001033	0000000A	293 MWC PRTNAME, OPNAME	fill in message with instruction
						294	
000003D2	B982	0022				295 XGR R2, R2	get M3 as U8
000003D6	4320	5007			00000007	296 IC R2, M3	and convert
000003DA	4E20	8EC8			000010C8	297 CVD R2, DECNUM	
000003DE	D211	8EB2 8E9C		000010B2	0000109C	298 MWC PRT3, EDIT	
000003E4	DE11	8EB2 8EC8		000010B2	000010C8	299 ED PRT3, DECNUM	
000003EA	D201	8E44 8EC0		00001044	000010C0	300 MWC PRTM3(2), PRT3+14	fill in message with m3 field
						301	
000003F0	4100	003F			0000003F	302 LA R0, PRTLNG	message length
000003F4	4110	8E08			00001008	303 LA R1, PRTLNE	messagfe address
000003F8	45F0	821A			0000041A	304 BAL R15, RPTERROR	
						306 *****	
						307 * continue after a failed test	
						308 *****	
				000003FC	00000001	309 FAILCONT EQU *	
000003FC	5800	8344			00000544	310 L R0, =F' 1'	set GLOBAL failed test indicator
00000400	5000	8E00			00001000	311 ST R0, FAILED	
						312	
00000404	41C0	C004			00000004	313 LA R12, 4(0, R12)	next test address
00000408	47F0	80DC			000002DC	314 B NEXTE6	
						316 *****	
						317 * end of testing; set ending psw	
						318 *****	
				0000040C	00000001	319 ENDTEST EQU *	
0000040C	5810	8E00			00001000	320 L R1, FAILED	did a test fail?
00000410	1211					321 LTR R1, R1	
00000412	4780	8318			00000518	322 BZ E0J	No, exit
00000416	47F0	8330			00000530	323 B FAILTEST	Yes, exit with BAD PSW
						324	

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT	
					389	*****
					390	* Normal completion or Abnormal termination PSWs
					391	*****
00000508	00020001	80000000			393	E0JPSW DC OD' 0' , X' 0002000180000000' , AD(0)
00000518	B2B2	8308		00000508	395	E0J LPSWE E0JPSW Normal completion
00000520	00020001	80000000			397	FAILPSW DC OD' 0' , X' 0002000180000000' , AD(X' BAD')
00000530	B2B2	8320		00000520	399	FAILTEST LPSWE FAILPSW Abnormal termination
					401	*****
					402	* Working Storage
					403	*****
00000534	00000000				405	CTLRO DS F CRO
00000538	00000000				406	DS F
0000053C					408	LTORG , Literals pool
0000053C	00000002				409	=F' 2'
00000540	00002160				410	=A(E6TESTS)
00000544	00000001				411	=F' 1'
00000548	00000003				412	=XL4' 3'
0000054C	0000				413	=H' 0'
0000054E	005F				414	=AL2(L' MSGMSG)
					415	
					416	* some constants
					417	
			00000400	00000001	418	K EQU 1024 One KB
			00001000	00000001	419	PAGE EQU (4*K) Size of one page
			00010000	00000001	420	K64 EQU (64*K) 64 KB
			00100000	00000001	421	MB EQU (K*K) 1 MB
					422	
					423	
			AABBCCDD	00000001	424	REG2PATT EQU X' AABBCCDD' Polluted Register pattern
			000000DD	00000001	425	REG2LOW EQU X' DD' (last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				526	*****
				527	* Macros to help build test tables
				528	*-----
				529	* VRR_I Macro to help build test tables
				530	*****
				531	MACRO
				532	VRR_I &INST, &MB, &CC
				533	. * &INST - VRS-d instruction under test
				534	. * &MB - P2 (bit 0), P1 (bit 2) and
				535	. * CS (bit 3)
				536	. * &CC - expected CC
				537	. *
				538	. * note: M4 - bit 0 IOM (always 0)
				539	. *
				540	. *
				541	LCLA &XCC(4) &CC has mask values for FAILED condition codes
				542	&XCC(1) SETA 7 CC != 0
				543	&XCC(2) SETA 11 CC != 1
				544	&XCC(3) SETA 13 CC != 2
				545	&XCC(4) SETA 14 CC != 3
				546	
				547	GBLA &TNUM
				548	&TNUM SETA &TNUM+1
				549	
				550	DS OFD
				551	USING *, R5 base for test data and test routine
				552	
				553	T&TNUM DC A(X&TNUM) address of test routine
				554	 DC H' &TNUM test number
				555	 DC XL1' 00'
				556	 DC HL1' &MB' &MB
				557	 DC HL1' &CC' cc
				558	 DC HL1' &XCC(&CC+1)' cc failed mask
				559	
				560	 DC CL8' &INST' instruction name
				561	 DC A(16) result length
				562	REA&TNUM DC A(RE&TNUM) result address
				563	. *
				564	* INSTRUCTION UNDER TEST ROUTINE
				565	X&TNUM DS OF
				566	 LG R1, R1FUDGE pollute R1
				567	 VL V1, RE&TNUM+8 get V1 source
				568	
				569	 &INST R1, V1, &MB test instruction
				570	
				571	 STG R1, R10OUTPUT save
				572	 EPSW R2, R0 exptract psw
				573	 ST R2, CCPSW to save CC
				574	
				575	 BR R11 return
				576	
				577	RE&TNUM DC OF
				578	 DROP R5
				579	
				580	 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				605 *****	
				606 * E6 VRR_I tests	
				607 *****	
00001188		00000000	00002227	608 ZVE6TST CSECT ,	
				609 DS 0F	
				611 PRINT DATA	
				612 *	
				613 * E650 VCVB - VECTOR CONVERT TO BINARY (32)	
				614 * E652 VCVBG - VECTOR CONVERT TO BINARY (64)	
				615 *	
				616 * VRR_I instr, m3, m4	
				617 * followed by	
				618 * r1 - expected result (64 bits) (even for VCVB)	
				619 * v1 - 16 byte packed decimal source	
				620	
				621 * -----	
				622 * VCVB - VECTOR CONVERT TO BINARY (32)	
				623 * -----	
				624 * VCVB simple	
00001188				625 VRR_I VCVB, 1, 0	
00001188		00001188		626+ DS 0FD	
00001188	000011A4			627+ USING *, R5	base for test data and test routine
0000118C	0001			628+T1 DC A(X1)	address of test routine
0000118E	00			629+ DC H' 1'	test number
0000118F	01			630+ DC XL1' 00'	
00001190	00			631+ DC HL1' 1'	&MB
00001191	07			632+ DC HL1' 0'	cc
00001192	E5C3E5C2 40404040			633+ DC HL1' 7'	cc failed mask
0000119C	00000010			634+ DC CL8' VCVB'	instruction name
000011A0	000011C8			635+ DC A(16)	result length
				636+REA1 DC A(RE1)	result address
				637+*	INSTRUCTION UNDER TEST ROUTINE
000011A4				638+X1 DS 0F	
000011A4	E310 8EE8 0004		000010E8	639+ LG R1, R1FUDGE	pollute R1
000011AA	E710 5048 0006		000011D0	640+ VL V1, RE1+8	get V1 source
000011B0	E611 0010 0050			641+ VCVB R1, V1, 1	test instruction
000011B6	E310 8F20 0024		00001120	642+ STG R1, R10UTPUT	save
000011BC	B98D 0020			643+ EPSW R2, R0	exptract psw
000011C0	5020 8ED8		000010D8	644+ ST R2, CCPSW	to save CC
000011C4	07FB			645+ BR R11	return
000011C8				646+RE1 DC 0F	
000011C8				647+ DROP R5	
000011C8	AABBCCDD 0000000A			648 DC XL08' AABBCCDD0000000A'	R1 result
000011D0	00000000 00000000			649 DC XL16' 0000000000000000000000000000000010C'	V1 source
000011D8	00000000 0000010C				
				650	
000011E0				651 VRR_I VCVB, 1, 0	
000011E0		000011E0		652+ DS 0FD	
000011E0	000011FC			653+ USING *, R5	base for test data and test routine
000011E4	0002			654+T2 DC A(X2)	address of test routine
000011E6	00			655+ DC H' 2'	test number
000011E6	00			656+ DC XL1' 00'	
000011E7	01			657+ DC HL1' 1'	&MB
000011E8	00			658+ DC HL1' 0'	cc

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000012A4	00000010			713+	DC	A(16)	result length
000012A8	000012D0			714+REA4	DC	A(RE4)	result address
				715+*			INSTRUCTION UNDER TEST ROUTINE
000012AC				716+X4	DS	0F	
000012AC	E310 8EE8 0004		000010E8	717+	LG	R1, R1FUDGE	pollute R1
000012B2	E710 5048 0006		000012D8	718+	VL	V1, RE4+8	get V1 source
000012B8	E611 0010 0050			719+	VCVB	R1, V1, 1	test instruction
000012BE	E310 8F20 0024		00001120	720+	STG	R1, R10UTPUT	save
000012C4	B98D 0020			721+	EPSW	R2, R0	exptract psw
000012C8	5020 8ED8		000010D8	722+	ST	R2, CCPSW	to save CC
000012CC	07FB			723+	BR	R11	return
000012D0				724+RE4	DC	0F	
000012D0				725+	DROP	R5	
000012D0	AABBCCDD FFF75EA0			726	DC	XL08' AABBCCDDFFF75EA0'	R1 result
000012D8	00000000 00000000			727	DC	XL16' 00000000000000000000000000565600D'	V1 source
000012E0	00000000 0565600D			728			
				729	VRR_I	VCVB, 1, 0	INT_MAX
000012E8				730+	DS	0FD	
000012E8		000012E8		731+	USING	*, R5	base for test data and test routine
000012E8	00001304			732+T5	DC	A(X5)	address of test routine
000012EC	0005			733+	DC	H' 5'	test number
000012EE	00			734+	DC	XL1' 00'	
000012EF	01			735+	DC	HL1' 1'	&MB
000012F0	00			736+	DC	HL1' 0'	cc
000012F1	07			737+	DC	HL1' 7'	cc failed mask
000012F2	E5C3E5C2 40404040			738+	DC	CL8' VCVB'	instruction name
000012FC	00000010			739+	DC	A(16)	result length
00001300	00001328			740+REA5	DC	A(RE5)	result address
				741+*			INSTRUCTION UNDER TEST ROUTINE
00001304				742+X5	DS	0F	
00001304	E310 8EE8 0004		000010E8	743+	LG	R1, R1FUDGE	pollute R1
0000130A	E710 5048 0006		00001330	744+	VL	V1, RE5+8	get V1 source
00001310	E611 0010 0050			745+	VCVB	R1, V1, 1	test instruction
00001316	E310 8F20 0024		00001120	746+	STG	R1, R10UTPUT	save
0000131C	B98D 0020			747+	EPSW	R2, R0	exptract psw
00001320	5020 8ED8		000010D8	748+	ST	R2, CCPSW	to save CC
00001324	07FB			749+	BR	R11	return
00001328				750+RE5	DC	0F	
00001328				751+	DROP	R5	
00001328	AABBCCDD 7FFFFFFF			752	DC	XL08' AABBCCDD7FFFFFFF'	R1 result
00001330	00000000 00000000			753	DC	XL16' 0000000000000000000000002147483647C'	V1 source
00001338	00000214 7483647C			754			
				755	VRR_I	VCVB, 1, 0	INT_MIN
00001340				756+	DS	0FD	
00001340		00001340		757+	USING	*, R5	base for test data and test routine
00001340	0000135C			758+T6	DC	A(X6)	address of test routine
00001344	0006			759+	DC	H' 6'	test number
00001346	00			760+	DC	XL1' 00'	
00001347	01			761+	DC	HL1' 1'	&MB
00001348	00			762+	DC	HL1' 0'	cc
00001349	07			763+	DC	HL1' 7'	cc failed mask
0000134A	E5C3E5C2 40404040			764+	DC	CL8' VCVB'	instruction name
00001354	00000010			765+	DC	A(16)	result length
00001358	00001380			766+REA6	DC	A(RE6)	result address

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				767+*		INSTRUCTION UNDER TEST ROUTINE	
0000135C				768+X6	DS	0F	
0000135C	E310 8EE8 0004		000010E8	769+	LG	R1, R1FUDGE	pollute R1
00001362	E710 5048 0006		00001388	770+	VL	V1, RE6+8	get V1 source
00001368	E611 0010 0050			771+	VCVB	R1, V1, 1	test instruction
0000136E	E310 8F20 0024		00001120	772+	STG	R1, R10UTPUT	save
00001374	B98D 0020			773+	EPSW	R2, R0	exptract psw
00001378	5020 8ED8		000010D8	774+	ST	R2, CCPSW	to save CC
0000137C	07FB			775+	BR	R11	return
00001380				776+RE6	DC	0F	
00001380				777+	DROP	R5	
00001380	AABBCCDD 80000000			778	DC	XL08' AABBCCDD80000000'	R1 result
00001388	00000000 00000000			779	DC	XL16' 0000000000000000000000002147483648D'	V1 source
00001390	00000214 7483648D						
				780			
				781	VRR_I	VCVB, 3, 0	UINT_MAX
00001398				782+	DS	0FD	
00001398		00001398		783+	USING	*, R5	base for test data and test routine
00001398	000013B4			784+T7	DC	A(X7)	address of test routine
0000139C	0007			785+	DC	H' 7'	test number
0000139E	00			786+	DC	XL1' 00'	
0000139F	03			787+	DC	HL1' 3'	&MB
000013A0	00			788+	DC	HL1' 0'	cc
000013A1	07			789+	DC	HL1' 7'	cc failed mask
000013A2	E5C3E5C2 40404040			790+	DC	CL8' VCVB'	instruction name
000013AC	00000010			791+	DC	A(16)	result length
000013B0	000013D8			792+REA7	DC	A(RE7)	result address
				793+*			INSTRUCTION UNDER TEST ROUTINE
000013B4				794+X7	DS	0F	
000013B4	E310 8EE8 0004		000010E8	795+	LG	R1, R1FUDGE	pollute R1
000013BA	E710 5048 0006		000013E0	796+	VL	V1, RE7+8	get V1 source
000013C0	E611 0030 0050			797+	VCVB	R1, V1, 3	test instruction
000013C6	E310 8F20 0024		00001120	798+	STG	R1, R10UTPUT	save
000013CC	B98D 0020			799+	EPSW	R2, R0	exptract psw
000013D0	5020 8ED8		000010D8	800+	ST	R2, CCPSW	to save CC
000013D4	07FB			801+	BR	R11	return
000013D8				802+RE7	DC	0F	
000013D8				803+	DROP	R5	
000013D8	AABBCCDD FFFFFFFF			804	DC	XL08' AABBCCDDFFFFFFFF'	R1 result
000013E0	00000000 00000000			805	DC	XL16' 0000000000000000000000004294967295C'	V1 source
000013E8	00000429 4967295C						
				806			
				807	VRR_I	VCVB, 3, 3	UINT_MAX +1
000013F0				808+	DS	0FD	
000013F0		000013F0		809+	USING	*, R5	base for test data and test routine
000013F0	0000140C			810+T8	DC	A(X8)	address of test routine
000013F4	0008			811+	DC	H' 8'	test number
000013F6	00			812+	DC	XL1' 00'	
000013F7	03			813+	DC	HL1' 3'	&MB
000013F8	03			814+	DC	HL1' 3'	cc
000013F9	0E			815+	DC	HL1' 14'	cc failed mask
000013FA	E5C3E5C2 40404040			816+	DC	CL8' VCVB'	instruction name
00001404	00000010			817+	DC	A(16)	result length
00001408	00001430			818+REA8	DC	A(RE8)	result address
				819+*			INSTRUCTION UNDER TEST ROUTINE
0000140C				820+X8	DS	0F	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000140C	E310 8EE8 0004		000010E8	821+	LG	R1, R1FUDGE	pollute R1
00001412	E710 5048 0006		00001438	822+	VL	V1, RE8+8	get V1 source
00001418	E611 0030 0050			823+	VCVB	R1, V1, 3	test instruction
0000141E	E310 8F20 0024		00001120	824+	STG	R1, R10UTPUT	save
00001424	B98D 0020			825+	EPSW	R2, R0	exptract psw
00001428	5020 8ED8		000010D8	826+	ST	R2, CCPSW	to save CC
0000142C	07FB			827+	BR	R11	return
00001430				828+RE8	DC	0F	
00001430				829+	DROP	R5	
00001430	AABBCCDD 00000000			830	DC	XL08' AABBCCDD00000000'	R1 result
00001438	00000000 00000000			831	DC	XL16' 0000000000000000000000004294967296C'	V1 source
00001440	00000429 4967296C						
				832			
				833	VRR_I	VCVB, 1, 3	
00001448				834+	DS	0FD	
00001448		00001448		835+	USING	*, R5	base for test data and test routine
00001448	00001464			836+T9	DC	A(X9)	address of test routine
0000144C	0009			837+	DC	H' 9'	test number
0000144E	00			838+	DC	XL1' 00'	
0000144F	01			839+	DC	HL1' 1'	&MB
00001450	03			840+	DC	HL1' 3'	cc
00001451	0E			841+	DC	HL1' 14'	cc failed mask
00001452	E5C3E5C2 40404040			842+	DC	CL8' VCVB'	instruction name
0000145C	00000010			843+	DC	A(16)	result length
00001460	00001488			844+REA9	DC	A(RE9)	result address
				845+*			INSTRUCTION UNDER TEST ROUTINE
00001464				846+X9	DS	0F	
00001464	E310 8EE8 0004		000010E8	847+	LG	R1, R1FUDGE	pollute R1
0000146A	E710 5048 0006		00001490	848+	VL	V1, RE9+8	get V1 source
00001470	E611 0010 0050			849+	VCVB	R1, V1, 1	test instruction
00001476	E310 8F20 0024		00001120	850+	STG	R1, R10UTPUT	save
0000147C	B98D 0020			851+	EPSW	R2, R0	exptract psw
00001480	5020 8ED8		000010D8	852+	ST	R2, CCPSW	to save CC
00001484	07FB			853+	BR	R11	return
00001488				854+RE9	DC	0F	
00001488				855+	DROP	R5	
00001488	AABBCCDD DF8E1660			856	DC	XL08' AABBCCDDDF8E1660'	R1 result
00001490	00000000 00000000			857	DC	XL16' 00000000000000000000000012340565600C'	V1 source
00001498	00001234 0565600C						
				858			
				859 * VCVB simple:	p2=1		
				860	VRR_I	VCVB, 9, 0	
000014A0				861+	DS	0FD	
000014A0		000014A0		862+	USING	*, R5	base for test data and test routine
000014A0	000014BC			863+T10	DC	A(X10)	address of test routine
000014A4	000A			864+	DC	H' 10'	test number
000014A6	00			865+	DC	XL1' 00'	
000014A7	09			866+	DC	HL1' 9'	&MB
000014A8	00			867+	DC	HL1' 0'	cc
000014A9	07			868+	DC	HL1' 7'	cc failed mask
000014AA	E5C3E5C2 40404040			869+	DC	CL8' VCVB'	instruction name
000014B4	00000010			870+	DC	A(16)	result length
000014B8	000014E0			871+REA10	DC	A(RE10)	result address
				872+*			INSTRUCTION UNDER TEST ROUTINE
000014BC				873+X10	DS	0F	
000014BC	E310 8EE8 0004		000010E8	874+	LG	R1, R1FUDGE	pollute R1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000014C2	E710 5048 0006		000014E8	875+	VL	V1, RE10+8	get V1 source
000014C8	E611 0090 0050			876+	VCVB	R1, V1, 9	test instruction
000014CE	E310 8F20 0024		00001120	877+	STG	R1, R10UTPUT	save
000014D4	B98D 0020			878+	EPSW	R2, R0	exptract psw
000014D8	5020 8ED8		000010D8	879+	ST	R2, CCPSW	to save CC
000014DC	07FB			880+	BR	R11	return
000014E0				881+RE10	DC	0F	
000014E0				882+	DROP	R5	
000014E0	AABBCCDD 0000000A			883	DC	XL08' AABBCCDD0000000A'	R1 result
000014E8	00000000 00000000			884	DC	XL16' 0000000000000000000000000000000010C'	V1 source
000014F0	00000000 0000010C						
				885			
				886	VRR_I	VCVB, 9, 0	
000014F8				887+	DS	0FD	
000014F8		000014F8		888+	USING	*, R5	base for test data and test routine
000014F8	00001514			889+T11	DC	A(X11)	address of test routine
000014FC	000B			890+	DC	H' 11'	test number
000014FE	00			891+	DC	XL1' 00'	
000014FF	09			892+	DC	HL1' 9'	&MB
00001500	00			893+	DC	HL1' 0'	cc
00001501	07			894+	DC	HL1' 7'	cc failed mask
00001502	E5C3E5C2 40404040			895+	DC	CL8' VCVB'	instruction name
0000150C	00000010			896+	DC	A(16)	result length
00001510	00001538			897+REA11	DC	A(RE11)	result address
				898+*			INSTRUCTION UNDER TEST ROUTINE
00001514				899+X11	DS	0F	
00001514	E310 8EE8 0004		000010E8	900+	LG	R1, R1FUDGE	pollute R1
0000151A	E710 5048 0006		00001540	901+	VL	V1, RE11+8	get V1 source
00001520	E611 0090 0050			902+	VCVB	R1, V1, 9	test instruction
00001526	E310 8F20 0024		00001120	903+	STG	R1, R10UTPUT	save
0000152C	B98D 0020			904+	EPSW	R2, R0	exptract psw
00001530	5020 8ED8		000010D8	905+	ST	R2, CCPSW	to save CC
00001534	07FB			906+	BR	R11	return
00001538				907+RE11	DC	0F	
00001538				908+	DROP	R5	
00001538	AABBCCDD 0000000A			909	DC	XL08' AABBCCDD0000000A'	R1 result
00001540	00000000 00000000			910	DC	XL16' 0000000000000000000000000000000010D'	V1 source
00001548	00000000 0000010D						
				911			
				912	VRR_I	VCVB, 9, 0	
00001550				913+	DS	0FD	
00001550		00001550		914+	USING	*, R5	base for test data and test routine
00001550	0000156C			915+T12	DC	A(X12)	address of test routine
00001554	000C			916+	DC	H' 12'	test number
00001556	00			917+	DC	XL1' 00'	
00001557	09			918+	DC	HL1' 9'	&MB
00001558	00			919+	DC	HL1' 0'	cc
00001559	07			920+	DC	HL1' 7'	cc failed mask
0000155A	E5C3E5C2 40404040			921+	DC	CL8' VCVB'	instruction name
00001564	00000010			922+	DC	A(16)	result length
00001568	00001590			923+REA12	DC	A(RE12)	result address
				924+*			INSTRUCTION UNDER TEST ROUTINE
0000156C				925+X12	DS	0F	
0000156C	E310 8EE8 0004		000010E8	926+	LG	R1, R1FUDGE	pollute R1
00001572	E710 5048 0006		00001598	927+	VL	V1, RE12+8	get V1 source
00001578	E611 0090 0050			928+	VCVB	R1, V1, 9	test instruction

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000157E	E310 8F20 0024		00001120	929+	STG	R1, R10OUTPUT	save
00001584	B98D 0020			930+	EPSW	R2, R0	exptract psw
00001588	5020 8ED8		000010D8	931+	ST	R2, CCPSW	to save CC
0000158C	07FB			932+	BR	R11	return
00001590				933+RE12	DC	OF	
00001590				934+	DROP	R5	
00001590	AABBCCDD 0008A160			935	DC	XL08' AABBCCDD0008A160'	R1 result
00001598	00000000 00000000			936	DC	XL16' 0000000000000000000000000565600C'	V1 source
000015A0	00000000 0565600C						
				937			
				938	VRR_I	VCVB, 9, 0	
000015A8				939+	DS	OFD	
000015A8		000015A8		940+	USING	*, R5	base for test data and test routine
000015A8	000015C4			941+T13	DC	A(X13)	address of test routine
000015AC	000D			942+	DC	H' 13'	test number
000015AE	00			943+	DC	XL1' 00'	
000015AF	09			944+	DC	HL1' 9'	&MB
000015B0	00			945+	DC	HL1' 0'	cc
000015B1	07			946+	DC	HL1' 7'	cc failed mask
000015B2	E5C3E5C2 40404040			947+	DC	CL8' VCVB'	instruction name
000015BC	00000010			948+	DC	A(16)	result length
000015C0	000015E8			949+REA13	DC	A(RE13)	result address
				950+*			INSTRUCTION UNDER TEST ROUTINE
000015C4				951+X13	DS	OF	
000015C4	E310 8EE8 0004		000010E8	952+	LG	R1, R1FUDGE	pollute R1
000015CA	E710 5048 0006		000015F0	953+	VL	V1, RE13+8	get V1 source
000015D0	E611 0090 0050			954+	VCVB	R1, V1, 9	test instruction
000015D6	E310 8F20 0024		00001120	955+	STG	R1, R10OUTPUT	save
000015DC	B98D 0020			956+	EPSW	R2, R0	exptract psw
000015E0	5020 8ED8		000010D8	957+	ST	R2, CCPSW	to save CC
000015E4	07FB			958+	BR	R11	return
000015E8				959+RE13	DC	OF	
000015E8				960+	DROP	R5	
000015E8	AABBCCDD 0008A160			961	DC	XL08' AABBCCDD0008A160'	R1 result
000015F0	00000000 00000000			962	DC	XL16' 0000000000000000000000000565600D'	V1 source
000015F8	00000000 0565600D						
				963			
				964	VRR_I	VCVB, 9, 0	INT_MAX
00001600				965+	DS	OFD	
00001600		00001600		966+	USING	*, R5	base for test data and test routine
00001600	0000161C			967+T14	DC	A(X14)	address of test routine
00001604	000E			968+	DC	H' 14'	test number
00001606	00			969+	DC	XL1' 00'	
00001607	09			970+	DC	HL1' 9'	&MB
00001608	00			971+	DC	HL1' 0'	cc
00001609	07			972+	DC	HL1' 7'	cc failed mask
0000160A	E5C3E5C2 40404040			973+	DC	CL8' VCVB'	instruction name
00001614	00000010			974+	DC	A(16)	result length
00001618	00001640			975+REA14	DC	A(RE14)	result address
				976+*			INSTRUCTION UNDER TEST ROUTINE
0000161C				977+X14	DS	OF	
0000161C	E310 8EE8 0004		000010E8	978+	LG	R1, R1FUDGE	pollute R1
00001622	E710 5048 0006		00001648	979+	VL	V1, RE14+8	get V1 source
00001628	E611 0090 0050			980+	VCVB	R1, V1, 9	test instruction
0000162E	E310 8F20 0024		00001120	981+	STG	R1, R10OUTPUT	save
00001634	B98D 0020			982+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001638	5020 8ED8		000010D8	983+	ST	R2, CCPSW	to save CC
0000163C	07FB			984+	BR	R11	return
00001640				985+RE14	DC	0F	
00001640				986+	DROP	R5	
00001640	AABBCCDD 7FFFFFFF			987	DC	XL08' AABBCCDD7FFFFFFF'	R1 result
00001648	00000000 00000000			988	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001650	00000214 7483647C						
				989			
				990	VRR_I	VCVB, 9, 3	INT_MIN
00001658				991+	DS	0FD	
00001658		00001658		992+	USING	*, R5	base for test data and test routine
00001658	00001674			993+T15	DC	A(X15)	address of test routine
0000165C	000F			994+	DC	H' 15'	test number
0000165E	00			995+	DC	XL1' 00'	
0000165F	09			996+	DC	HL1' 9'	&MB
00001660	03			997+	DC	HL1' 3'	cc
00001661	0E			998+	DC	HL1' 14'	cc failed mask
00001662	E5C3E5C2 40404040			999+	DC	CL8' VCVB'	instruction name
0000166C	00000010			1000+	DC	A(16)	result length
00001670	00001698			1001+REA15	DC	A(RE15)	result address
				1002+*			INSTRUCTION UNDER TEST ROUTINE
00001674				1003+X15	DS	0F	
00001674	E310 8EE8 0004		000010E8	1004+	LG	R1, R1FUDGE	pollute R1
0000167A	E710 5048 0006		000016A0	1005+	VL	V1, RE15+8	get V1 source
00001680	E611 0090 0050			1006+	VCVB	R1, V1, 9	test instruction
00001686	E310 8F20 0024		00001120	1007+	STG	R1, R10UTPUT	save
0000168C	B98D 0020			1008+	EPSW	R2, R0	exptract psw
00001690	5020 8ED8		000010D8	1009+	ST	R2, CCPSW	to save CC
00001694	07FB			1010+	BR	R11	return
00001698				1011+RE15	DC	0F	
00001698				1012+	DROP	R5	
00001698	AABBCCDD 80000000			1013	DC	XL08' AABBCCDD80000000'	R1 result
000016A0	00000000 00000000			1014	DC	XL16' 000000000000000000000002147483648D'	V1 source
000016A8	00000214 7483648D						
				1015			
				1016	VRR_I	VCVB, 11, 0	UINT_MAX
000016B0				1017+	DS	0FD	
000016B0		000016B0		1018+	USING	*, R5	base for test data and test routine
000016B0	000016CC			1019+T16	DC	A(X16)	address of test routine
000016B4	0010			1020+	DC	H' 16'	test number
000016B6	00			1021+	DC	XL1' 00'	
000016B7	0B			1022+	DC	HL1' 11'	&MB
000016B8	00			1023+	DC	HL1' 0'	cc
000016B9	07			1024+	DC	HL1' 7'	cc failed mask
000016BA	E5C3E5C2 40404040			1025+	DC	CL8' VCVB'	instruction name
000016C4	00000010			1026+	DC	A(16)	result length
000016C8	000016F0			1027+REA16	DC	A(RE16)	result address
				1028+*			INSTRUCTION UNDER TEST ROUTINE
000016CC				1029+X16	DS	0F	
000016CC	E310 8EE8 0004		000010E8	1030+	LG	R1, R1FUDGE	pollute R1
000016D2	E710 5048 0006		000016F8	1031+	VL	V1, RE16+8	get V1 source
000016D8	E611 00B0 0050			1032+	VCVB	R1, V1, 11	test instruction
000016DE	E310 8F20 0024		00001120	1033+	STG	R1, R10UTPUT	save
000016E4	B98D 0020			1034+	EPSW	R2, R0	exptract psw
000016E8	5020 8ED8		000010D8	1035+	ST	R2, CCPSW	to save CC
000016EC	07FB			1036+	BR	R11	return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016F0				1037+RE16	DC	0F	
000016F0				1038+	DROP	R5	
000016F0	AABBCCDD FFFFFFFF			1039	DC	XL08' AABBCCDDFFFFFFFF'	R1 result
000016F8	00000000 00000000			1040	DC	XL16' 0000000000000000000000004294967295C'	V1 source
00001700	00000429 4967295C						
				1041			
				1042	VRR_I	VCVB, 11, 3	UINT_MAX +1
00001708				1043+	DS	0FD	
00001708		00001708		1044+	USING	*, R5	base for test data and test routine
00001708	00001724			1045+T17	DC	A(X17)	address of test routine
0000170C	0011			1046+	DC	H' 17'	test number
0000170E	00			1047+	DC	XL1' 00'	
0000170F	0B			1048+	DC	HL1' 11'	&MB
00001710	03			1049+	DC	HL1' 3'	cc
00001711	0E			1050+	DC	HL1' 14'	cc failed mask
00001712	E5C3E5C2 40404040			1051+	DC	CL8' VCVB'	instruction name
0000171C	00000010			1052+	DC	A(16)	result length
00001720	00001748			1053+REA17	DC	A(RE17)	result address
				1054+*			INSTRUCTION UNDER TEST ROUTINE
00001724				1055+X17	DS	0F	
00001724	E310 8EE8 0004		000010E8	1056+	LG	R1, R1FUDGE	pollute R1
0000172A	E710 5048 0006		00001750	1057+	VL	V1, RE17+8	get V1 source
00001730	E611 00B0 0050			1058+	VCVB	R1, V1, 11	test instruction
00001736	E310 8F20 0024		00001120	1059+	STG	R1, R10UTPUT	save
0000173C	B98D 0020			1060+	EPSW	R2, R0	exptract psw
00001740	5020 8ED8		000010D8	1061+	ST	R2, CCPSW	to save CC
00001744	07FB			1062+	BR	R11	return
00001748				1063+RE17	DC	0F	
00001748				1064+	DROP	R5	
00001748	AABBCCDD 00000000			1065	DC	XL08' AABBCCDD00000000'	R1 result
00001750	00000000 00000000			1066	DC	XL16' 0000000000000000000000004294967296C'	V1 source
00001758	00000429 4967296C						
				1067			
				1068	VRR_I	VCVB, 9, 3	
00001760				1069+	DS	0FD	
00001760		00001760		1070+	USING	*, R5	base for test data and test routine
00001760	0000177C			1071+T18	DC	A(X18)	address of test routine
00001764	0012			1072+	DC	H' 18'	test number
00001766	00			1073+	DC	XL1' 00'	
00001767	09			1074+	DC	HL1' 9'	&MB
00001768	03			1075+	DC	HL1' 3'	cc
00001769	0E			1076+	DC	HL1' 14'	cc failed mask
0000176A	E5C3E5C2 40404040			1077+	DC	CL8' VCVB'	instruction name
00001774	00000010			1078+	DC	A(16)	result length
00001778	000017A0			1079+REA18	DC	A(RE18)	result address
				1080+*			INSTRUCTION UNDER TEST ROUTINE
0000177C				1081+X18	DS	0F	
0000177C	E310 8EE8 0004		000010E8	1082+	LG	R1, R1FUDGE	pollute R1
00001782	E710 5048 0006		000017A8	1083+	VL	V1, RE18+8	get V1 source
00001788	E611 0090 0050			1084+	VCVB	R1, V1, 9	test instruction
0000178E	E310 8F20 0024		00001120	1085+	STG	R1, R10UTPUT	save
00001794	B98D 0020			1086+	EPSW	R2, R0	exptract psw
00001798	5020 8ED8		000010D8	1087+	ST	R2, CCPSW	to save CC
0000179C	07FB			1088+	BR	R11	return
000017A0				1089+RE18	DC	0F	
000017A0				1090+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000017A0	AABBCCDD DF8E1660			1091	DC	XL08' AABBCCDDDF8E1660'	R1 result
000017A8	00000000 00000000			1092	DC	XL16' 0000000000000000000012340565600C'	V1 source
000017B0	00001234 0565600C						
				1093			
				1094	*	-----	
				1095	*	VCVBG - VECTOR CONVERT TO BINARY (64)	
				1096	*	-----	
				1097	*	VCVBG simple	
				1098	VRR_I	VCVBG, 1, 0	
000017B8				1099+	DS	OFD	
000017B8		000017B8		1100+	USING	*, R5	base for test data and test routine
000017B8	000017D4			1101+T19	DC	A(X19)	address of test routine
000017BC	0013			1102+	DC	H' 19'	test number
000017BE	00			1103+	DC	XL1' 00'	
000017BF	01			1104+	DC	HL1' 1'	&MB
000017C0	00			1105+	DC	HL1' 0'	cc
000017C1	07			1106+	DC	HL1' 7'	cc failed mask
000017C2	E5C3E5C2 C7404040			1107+	DC	CL8' VCVBG'	instruction name
000017CC	00000010			1108+	DC	A(16)	result length
000017D0	000017F8			1109+REA19	DC	A(RE19)	result address
				1110+	*		INSTRUCTION UNDER TEST ROUTINE
000017D4				1111+X19	DS	OF	
000017D4	E310 8EE8 0004		000010E8	1112+	LG	R1, R1FUDGE	pollute R1
000017DA	E710 5048 0006		00001800	1113+	VL	V1, RE19+8	get V1 source
000017E0	E611 0010 0052			1114+	VCVBG	R1, V1, 1	test instruction
000017E6	E310 8F20 0024		00001120	1115+	STG	R1, R10UTPUT	save
000017EC	B98D 0020			1116+	EPSW	R2, R0	exptract psw
000017F0	5020 8ED8		000010D8	1117+	ST	R2, CCPSW	to save CC
000017F4	07FB			1118+	BR	R11	return
000017F8				1119+RE19	DC	OF	
000017F8				1120+	DROP	R5	
000017F8	00000000 0000000A			1121	DC	XL08' 0000000000000000A'	R1 result
00001800	00000000 00000000			1122	DC	XL16' 000000000000000000000000000010C'	V1 source
00001808	00000000 0000010C						
				1123			
				1124	VRR_I	VCVBG, 1, 0	
00001810				1125+	DS	OFD	
00001810		00001810		1126+	USING	*, R5	base for test data and test routine
00001810	0000182C			1127+T20	DC	A(X20)	address of test routine
00001814	0014			1128+	DC	H' 20'	test number
00001816	00			1129+	DC	XL1' 00'	
00001817	01			1130+	DC	HL1' 1'	&MB
00001818	00			1131+	DC	HL1' 0'	cc
00001819	07			1132+	DC	HL1' 7'	cc failed mask
0000181A	E5C3E5C2 C7404040			1133+	DC	CL8' VCVBG'	instruction name
00001824	00000010			1134+	DC	A(16)	result length
00001828	00001850			1135+REA20	DC	A(RE20)	result address
				1136+	*		INSTRUCTION UNDER TEST ROUTINE
0000182C				1137+X20	DS	OF	
0000182C	E310 8EE8 0004		000010E8	1138+	LG	R1, R1FUDGE	pollute R1
00001832	E710 5048 0006		00001858	1139+	VL	V1, RE20+8	get V1 source
00001838	E611 0010 0052			1140+	VCVBG	R1, V1, 1	test instruction
0000183E	E310 8F20 0024		00001120	1141+	STG	R1, R10UTPUT	save
00001844	B98D 0020			1142+	EPSW	R2, R0	exptract psw
00001848	5020 8ED8		000010D8	1143+	ST	R2, CCPSW	to save CC
0000184C	07FB			1144+	BR	R11	return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001850				1145+RE20	DC	0F
00001850				1146+	DROP	R5
00001850	FFFFFFFF FFFFFFFF6			1147	DC	XL08' FFFFFFFF6'
00001858	00000000 00000000			1148	DC	XL16' 000000000000000000000000000010D'
00001860	00000000 0000010D					R1 result V1 source
				1149		
				1150	VRR_I	VCVBG, 1, 0
00001868				1151+	DS	0FD
00001868		00001868		1152+	USING	*, R5
00001868	00001884			1153+T21	DC	A(X21)
0000186C	0015			1154+	DC	H' 21'
0000186E	00			1155+	DC	XL1' 00'
0000186F	01			1156+	DC	HL1' 1'
00001870	00			1157+	DC	HL1' 0'
00001871	07			1158+	DC	HL1' 7'
00001872	E5C3E5C2 C7404040			1159+	DC	CL8' VCVBG'
0000187C	00000010			1160+	DC	A(16)
00001880	000018A8			1161+REA21	DC	A(RE21)
				1162+*		INSTRUCTION UNDER TEST ROUTINE
00001884				1163+X21	DS	0F
00001884	E310 8EE8 0004		000010E8	1164+	LG	R1, R1FUDGE
0000188A	E710 5048 0006		000018B0	1165+	VL	V1, RE21+8
00001890	E611 0010 0052			1166+	VCVBG	R1, V1, 1
00001896	E310 8F20 0024		00001120	1167+	STG	R1, R10UTPUT
0000189C	B98D 0020			1168+	EPSW	R2, R0
000018A0	5020 8ED8		000010D8	1169+	ST	R2, CCPSW
000018A4	07FB			1170+	BR	R11
000018A8				1171+RE21	DC	0F
000018A8				1172+	DROP	R5
000018A8	00000000 0008A160			1173	DC	XL08' 000000000008A160'
000018B0	00000000 00000000			1174	DC	XL16' 0000000000000000000000000565600C'
000018B8	00000000 0565600C					R1 result V1 source
				1175		
				1176	VRR_I	VCVBG, 1, 0
000018C0				1177+	DS	0FD
000018C0		000018C0		1178+	USING	*, R5
000018C0	000018DC			1179+T22	DC	A(X22)
000018C4	0016			1180+	DC	H' 22'
000018C6	00			1181+	DC	XL1' 00'
000018C7	01			1182+	DC	HL1' 1'
000018C8	00			1183+	DC	HL1' 0'
000018C9	07			1184+	DC	HL1' 7'
000018CA	E5C3E5C2 C7404040			1185+	DC	CL8' VCVBG'
000018D4	00000010			1186+	DC	A(16)
000018D8	00001900			1187+REA22	DC	A(RE22)
				1188+*		INSTRUCTION UNDER TEST ROUTINE
000018DC				1189+X22	DS	0F
000018DC	E310 8EE8 0004		000010E8	1190+	LG	R1, R1FUDGE
000018E2	E710 5048 0006		00001908	1191+	VL	V1, RE22+8
000018E8	E611 0010 0052			1192+	VCVBG	R1, V1, 1
000018EE	E310 8F20 0024		00001120	1193+	STG	R1, R10UTPUT
000018F4	B98D 0020			1194+	EPSW	R2, R0
000018F8	5020 8ED8		000010D8	1195+	ST	R2, CCPSW
000018FC	07FB			1196+	BR	R11
00001900				1197+RE22	DC	0F
00001900				1198+	DROP	R5

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001900	FFFFFFFF FFF75EA0			1199	DC	XL08' FFFFFFFFFF75EA0'	R1 result
00001908	00000000 00000000			1200	DC	XL16' 0000000000000000000000000565600D'	V1 source
00001910	00000000 0565600D						
				1201			
				1202	VRR_I	VCVBG, 1, 0	INT_MAX
00001918				1203+	DS	OFD	
00001918		00001918		1204+	USING	*, R5	base for test data and test routine
00001918	00001934			1205+T23	DC	A(X23)	address of test routine
0000191C	0017			1206+	DC	H' 23'	test number
0000191E	00			1207+	DC	XL1' 00'	
0000191F	01			1208+	DC	HL1' 1'	&MB
00001920	00			1209+	DC	HL1' 0'	cc
00001921	07			1210+	DC	HL1' 7'	cc failed mask
00001922	E5C3E5C2 C7404040			1211+	DC	CL8' VCVBG'	instruction name
0000192C	00000010			1212+	DC	A(16)	result length
00001930	00001958			1213+REA23	DC	A(RE23)	result address
				1214+*			INSTRUCTION UNDER TEST ROUTINE
00001934				1215+X23	DS	OF	
00001934	E310 8EE8 0004		000010E8	1216+	LG	R1, R1FUDGE	pollute R1
0000193A	E710 5048 0006		00001960	1217+	VL	V1, RE23+8	get V1 source
00001940	E611 0010 0052			1218+	VCVBG	R1, V1, 1	test instruction
00001946	E310 8F20 0024		00001120	1219+	STG	R1, R10UTPUT	save
0000194C	B98D 0020			1220+	EPSW	R2, R0	exptract psw
00001950	5020 8ED8		000010D8	1221+	ST	R2, CCPSW	to save CC
00001954	07FB			1222+	BR	R11	return
00001958				1223+RE23	DC	OF	
00001958				1224+	DROP	R5	
00001958	00000000 7FFFFFFF			1225	DC	XL08' 000000007FFFFFFF'	R1 result
00001960	00000000 00000000			1226	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001968	00000214 7483647C						
				1227			
				1228	VRR_I	VCVBG, 1, 0	INT_MIN
00001970				1229+	DS	OFD	
00001970		00001970		1230+	USING	*, R5	base for test data and test routine
00001970	0000198C			1231+T24	DC	A(X24)	address of test routine
00001974	0018			1232+	DC	H' 24'	test number
00001976	00			1233+	DC	XL1' 00'	
00001977	01			1234+	DC	HL1' 1'	&MB
00001978	00			1235+	DC	HL1' 0'	cc
00001979	07			1236+	DC	HL1' 7'	cc failed mask
0000197A	E5C3E5C2 C7404040			1237+	DC	CL8' VCVBG'	instruction name
00001984	00000010			1238+	DC	A(16)	result length
00001988	000019B0			1239+REA24	DC	A(RE24)	result address
				1240+*			INSTRUCTION UNDER TEST ROUTINE
0000198C				1241+X24	DS	OF	
0000198C	E310 8EE8 0004		000010E8	1242+	LG	R1, R1FUDGE	pollute R1
00001992	E710 5048 0006		000019B8	1243+	VL	V1, RE24+8	get V1 source
00001998	E611 0010 0052			1244+	VCVBG	R1, V1, 1	test instruction
0000199E	E310 8F20 0024		00001120	1245+	STG	R1, R10UTPUT	save
000019A4	B98D 0020			1246+	EPSW	R2, R0	exptract psw
000019A8	5020 8ED8		000010D8	1247+	ST	R2, CCPSW	to save CC
000019AC	07FB			1248+	BR	R11	return
000019B0				1249+RE24	DC	OF	
000019B0				1250+	DROP	R5	
000019B0	FFFFFFFF 80000000			1251	DC	XL08' FFFFFFFFFF80000000'	R1 result
000019B8	00000000 00000000			1252	DC	XL16' 000000000000000000000002147483648D'	V1 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000019C0	00000214 7483648D			1253		
				1254	VRR_I VCVBG, 1, 0	UINT_MAX
000019C8				1255+	DS OFD	
000019C8		000019C8		1256+	USING *, R5	base for test data and test routine
000019C8	000019E4			1257+T25	DC A(X25)	address of test routine
000019CC	0019			1258+	DC H' 25'	test number
000019CE	00			1259+	DC XL1' 00'	
000019CF	01			1260+	DC HL1' 1'	&MB
000019D0	00			1261+	DC HL1' 0'	cc
000019D1	07			1262+	DC HL1' 7'	cc failed mask
000019D2	E5C3E5C2 C7404040			1263+	DC CL8' VCVBG'	instruction name
000019DC	00000010			1264+	DC A(16)	result length
000019E0	00001A08			1265+REA25	DC A(RE25)	result address
				1266+*		INSTRUCTION UNDER TEST ROUTINE
000019E4				1267+X25	DS OF	
000019E4	E310 8EE8 0004		000010E8	1268+	LG R1, R1FUDGE	pollute R1
000019EA	E710 5048 0006		00001A10	1269+	VL V1, RE25+8	get V1 source
000019F0	E611 0010 0052			1270+	VCVBG R1, V1, 1	test instruction
000019F6	E310 8F20 0024		00001120	1271+	STG R1, R10UTPUT	save
000019FC	B98D 0020			1272+	EPSW R2, R0	exptract psw
00001A00	5020 8ED8		000010D8	1273+	ST R2, CCPSW	to save CC
00001A04	07FB			1274+	BR R11	return
00001A08				1275+RE25	DC OF	
00001A08				1276+	DROP R5	
00001A08	00000000 FFFFFFFF			1277	DC XL08' 00000000FFFFFFFF'	R1 result
00001A10	00000000 00000000			1278	DC XL16' 0000000000000000000000004294967295C'	V1 source
00001A18	00000429 4967295C					
				1279		
				1280	VRR_I VCVBG, 1, 0	UINT_MAX +1
00001A20				1281+	DS OFD	
00001A20		00001A20		1282+	USING *, R5	base for test data and test routine
00001A20	00001A3C			1283+T26	DC A(X26)	address of test routine
00001A24	001A			1284+	DC H' 26'	test number
00001A26	00			1285+	DC XL1' 00'	
00001A27	01			1286+	DC HL1' 1'	&MB
00001A28	00			1287+	DC HL1' 0'	cc
00001A29	07			1288+	DC HL1' 7'	cc failed mask
00001A2A	E5C3E5C2 C7404040			1289+	DC CL8' VCVBG'	instruction name
00001A34	00000010			1290+	DC A(16)	result length
00001A38	00001A60			1291+REA26	DC A(RE26)	result address
				1292+*		INSTRUCTION UNDER TEST ROUTINE
00001A3C				1293+X26	DS OF	
00001A3C	E310 8EE8 0004		000010E8	1294+	LG R1, R1FUDGE	pollute R1
00001A42	E710 5048 0006		00001A68	1295+	VL V1, RE26+8	get V1 source
00001A48	E611 0010 0052			1296+	VCVBG R1, V1, 1	test instruction
00001A4E	E310 8F20 0024		00001120	1297+	STG R1, R10UTPUT	save
00001A54	B98D 0020			1298+	EPSW R2, R0	exptract psw
00001A58	5020 8ED8		000010D8	1299+	ST R2, CCPSW	to save CC
00001A5C	07FB			1300+	BR R11	return
00001A60				1301+RE26	DC OF	
00001A60				1302+	DROP R5	
00001A60	00000001 00000000			1303	DC XL08' 0000000100000000'	R1 result
00001A68	00000000 00000000			1304	DC XL16' 0000000000000000000000004294967296C'	V1 source
00001A70	00000429 4967296C					
				1305		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001A78				1306	VRR_I	VCVBG, 1, 0	
00001A78				1307+	DS	OFD	
00001A78		00001A78		1308+	USING	*, R5	base for test data and test routine
00001A78	00001A94			1309+T27	DC	A(X27)	address of test routine
00001A7C	001B			1310+	DC	H' 27'	test number
00001A7E	00			1311+	DC	XL1' 00'	
00001A7F	01			1312+	DC	HL1' 1'	&MB
00001A80	00			1313+	DC	HL1' 0'	cc
00001A81	07			1314+	DC	HL1' 7'	cc failed mask
00001A82	E5C3E5C2 C7404040			1315+	DC	CL8' VCVBG'	instruction name
00001A8C	00000010			1316+	DC	A(16)	result length
00001A90	00001AB8			1317+REA27	DC	A(RE27)	result address
				1318+*			INSTRUCTION UNDER TEST ROUTINE
00001A94				1319+X27	DS	OF	
00001A94	E310 8EE8 0004		000010E8	1320+	LG	R1, R1FUDGE	pollute R1
00001A9A	E710 5048 0006		00001AC0	1321+	VL	V1, RE27+8	get V1 source
00001AA0	E611 0010 0052			1322+	VCVBG	R1, V1, 1	test instruction
00001AA6	E310 8F20 0024		00001120	1323+	STG	R1, R10UTPUT	save
00001AAC	B98D 0020			1324+	EPSW	R2, R0	exptract psw
00001AB0	5020 8ED8		000010D8	1325+	ST	R2, CCPSW	to save CC
00001AB4	07FB			1326+	BR	R11	return
00001AB8				1327+RE27	DC	OF	
00001AB8				1328+	DROP	R5	
00001AB8	00000002 DF8E1660			1329	DC	XL08' 00000002DF8E1660'	R1 result
00001AC0	00000000 00000000			1330	DC	XL16' 00000000000000000000000012340565600C'	V1 source
00001AC8	00001234 0565600C						
				1331			
00001AD0				1332	VRR_I	VCVBG, 1, 0	LONG_MAX
00001AD0				1333+	DS	OFD	
00001AD0		00001AD0		1334+	USING	*, R5	base for test data and test routine
00001AD0	00001AEC			1335+T28	DC	A(X28)	address of test routine
00001AD4	001C			1336+	DC	H' 28'	test number
00001AD6	00			1337+	DC	XL1' 00'	
00001AD7	01			1338+	DC	HL1' 1'	&MB
00001AD8	00			1339+	DC	HL1' 0'	cc
00001AD9	07			1340+	DC	HL1' 7'	cc failed mask
00001ADA	E5C3E5C2 C7404040			1341+	DC	CL8' VCVBG'	instruction name
00001AE4	00000010			1342+	DC	A(16)	result length
00001AE8	00001B10			1343+REA28	DC	A(RE28)	result address
				1344+*			INSTRUCTION UNDER TEST ROUTINE
00001AEC				1345+X28	DS	OF	
00001AEC	E310 8EE8 0004		000010E8	1346+	LG	R1, R1FUDGE	pollute R1
00001AF2	E710 5048 0006		00001B18	1347+	VL	V1, RE28+8	get V1 source
00001AF8	E611 0010 0052			1348+	VCVBG	R1, V1, 1	test instruction
00001AFE	E310 8F20 0024		00001120	1349+	STG	R1, R10UTPUT	save
00001B04	B98D 0020			1350+	EPSW	R2, R0	exptract psw
00001B08	5020 8ED8		000010D8	1351+	ST	R2, CCPSW	to save CC
00001B0C	07FB			1352+	BR	R11	return
00001B10				1353+RE28	DC	OF	
00001B10				1354+	DROP	R5	
00001B10	7FFFFFFF FFFFFFFF			1355	DC	XL08' 7FFFFFFF7FFFFFFF'	R1 result
00001B18	00000000 00009223			1356	DC	XL16' 000000000000009223372036854775807C'	V1 source
00001B20	37203685 4775807C						
				1357			
00001B28				1358	VRR_I	VCVBG, 1, 0	LONG_MIN
				1359+	DS	OFD	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001B28		00001B28		1360+	USING *,R5	base for test data and test routine
00001B28	00001B44			1361+T29	DC A(X29)	address of test routine
00001B2C	001D			1362+	DC H' 29'	test number
00001B2E	00			1363+	DC XL1' 00'	
00001B2F	01			1364+	DC HL1' 1'	&MB
00001B30	00			1365+	DC HL1' 0'	cc
00001B31	07			1366+	DC HL1' 7'	cc failed mask
00001B32	E5C3E5C2 C7404040			1367+	DC CL8' VCVBG'	instruction name
00001B3C	00000010			1368+	DC A(16)	result length
00001B40	00001B68			1369+REA29	DC A(RE29)	result address
				1370+*		INSTRUCTION UNDER TEST ROUTINE
00001B44				1371+X29	DS 0F	
00001B44	E310 8EE8 0004		000010E8	1372+	LG R1, R1FUDGE	pollute R1
00001B4A	E710 5048 0006		00001B70	1373+	VL V1, RE29+8	get V1 source
00001B50	E611 0010 0052			1374+	VCVBG R1, V1, 1	test instruction
00001B56	E310 8F20 0024		00001120	1375+	STG R1, R10UTPUT	save
00001B5C	B98D 0020			1376+	EPSW R2, R0	exptract psw
00001B60	5020 8ED8		000010D8	1377+	ST R2, CCPSW	to save CC
00001B64	07FB			1378+	BR R11	return
00001B68				1379+RE29	DC 0F	
00001B68				1380+	DROP R5	
00001B68	80000000 00000000			1381	DC XL08' 8000000000000000'	R1 result
00001B70	00000000 00009223			1382	DC XL16' 0000000000009223372036854775808D'	V1 source
00001B78	37203685 4775808D					
				1383		
				1384	VRR_I VCVBG, 3, 0	ULONG_MAX
00001B80		00001B80		1385+	DS 0FD	
00001B80				1386+	USING *,R5	base for test data and test routine
00001B80	00001B9C			1387+T30	DC A(X30)	address of test routine
00001B84	001E			1388+	DC H' 30'	test number
00001B86	00			1389+	DC XL1' 00'	
00001B87	03			1390+	DC HL1' 3'	&MB
00001B88	00			1391+	DC HL1' 0'	cc
00001B89	07			1392+	DC HL1' 7'	cc failed mask
00001B8A	E5C3E5C2 C7404040			1393+	DC CL8' VCVBG'	instruction name
00001B94	00000010			1394+	DC A(16)	result length
00001B98	00001BC0			1395+REA30	DC A(RE30)	result address
				1396+*		INSTRUCTION UNDER TEST ROUTINE
00001B9C				1397+X30	DS 0F	
00001B9C	E310 8EE8 0004		000010E8	1398+	LG R1, R1FUDGE	pollute R1
00001BA2	E710 5048 0006		00001BC8	1399+	VL V1, RE30+8	get V1 source
00001BA8	E611 0030 0052			1400+	VCVBG R1, V1, 3	test instruction
00001BAE	E310 8F20 0024		00001120	1401+	STG R1, R10UTPUT	save
00001BB4	B98D 0020			1402+	EPSW R2, R0	exptract psw
00001BB8	5020 8ED8		000010D8	1403+	ST R2, CCPSW	to save CC
00001BBC	07FB			1404+	BR R11	return
00001BC0				1405+RE30	DC 0F	
00001BC0				1406+	DROP R5	
00001BC0	FFFFFFFF FFFFFFFF			1407	DC XL08' FFFFFFFFFFFFFFFFFF'	R1 result
00001BC8	00000000 00018446			1408	DC XL16' 0000000000018446744073709551615C'	V1 source
00001BD0	74407370 9551615C					
				1409		
				1410	VRR_I VCVBG, 3, 3	ULONG_MAX +1
00001BD8		00001BD8		1411+	DS 0FD	
00001BD8				1412+	USING *,R5	base for test data and test routine
00001BD8	00001BF4			1413+T31	DC A(X31)	address of test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001BDC	001F			1414+	DC	H' 31'	test number
00001BDE	00			1415+	DC	XL1' 00'	
00001BDF	03			1416+	DC	HL1' 3'	&MB
00001BE0	03			1417+	DC	HL1' 3'	cc
00001BE1	0E			1418+	DC	HL1' 14'	cc failed mask
00001BE2	E5C3E5C2 C7404040			1419+	DC	CL8' VCVBG'	instruction name
00001BEC	00000010			1420+	DC	A(16)	result length
00001BF0	00001C18			1421+REA31	DC	A(RE31)	result address
				1422+*			INSTRUCTION UNDER TEST ROUTINE
00001BF4				1423+X31	DS	0F	
00001BF4	E310 8EE8 0004		000010E8	1424+	LG	R1, R1FUDGE	pollute R1
00001BFA	E710 5048 0006		00001C20	1425+	VL	V1, RE31+8	get V1 source
00001C00	E611 0030 0052			1426+	VCVBG	R1, V1, 3	test instruction
00001C06	E310 8F20 0024		00001120	1427+	STG	R1, R10UTPUT	save
00001C0C	B98D 0020			1428+	EPSW	R2, R0	exptract psw
00001C10	5020 8ED8		000010D8	1429+	ST	R2, CCPSW	to save CC
00001C14	07FB			1430+	BR	R11	return
00001C18				1431+RE31	DC	0F	
00001C18				1432+	DROP	R5	
00001C18	00000000 00000000			1433	DC	XL08' 00000000000000000'	R1 result
00001C20	00000000 00018446			1434	DC	XL16' 0000000000018446744073709551616C'	V1 source
00001C28	74407370 9551616C						
				1435			
00001C30				1436	VRR_I	VCVBG, 3, 3	ULONG_MAX +11
00001C30		00001C30		1437+	DS	0FD	
00001C30	00001C4C			1438+	USING	*, R5	base for test data and test routine
00001C34	0020			1439+T32	DC	A(X32)	address of test routine
00001C36	00			1440+	DC	H' 32'	test number
00001C36	00			1441+	DC	XL1' 00'	
00001C37	03			1442+	DC	HL1' 3'	&MB
00001C38	03			1443+	DC	HL1' 3'	cc
00001C39	0E			1444+	DC	HL1' 14'	cc failed mask
00001C3A	E5C3E5C2 C7404040			1445+	DC	CL8' VCVBG'	instruction name
00001C44	00000010			1446+	DC	A(16)	result length
00001C48	00001C70			1447+REA32	DC	A(RE32)	result address
				1448+*			INSTRUCTION UNDER TEST ROUTINE
00001C4C				1449+X32	DS	0F	
00001C4C	E310 8EE8 0004		000010E8	1450+	LG	R1, R1FUDGE	pollute R1
00001C52	E710 5048 0006		00001C78	1451+	VL	V1, RE32+8	get V1 source
00001C58	E611 0030 0052			1452+	VCVBG	R1, V1, 3	test instruction
00001C5E	E310 8F20 0024		00001120	1453+	STG	R1, R10UTPUT	save
00001C64	B98D 0020			1454+	EPSW	R2, R0	exptract psw
00001C68	5020 8ED8		000010D8	1455+	ST	R2, CCPSW	to save CC
00001C6C	07FB			1456+	BR	R11	return
00001C70				1457+RE32	DC	0F	
00001C70				1458+	DROP	R5	
00001C70	00000000 0000000A			1459	DC	XL08' 0000000000000000A'	R1 result
00001C78	00000000 00018446			1460	DC	XL16' 0000000000018446744073709551626C'	V1 source
00001C80	74407370 9551626C						
				1461			
				1462 * VCVBG simple: p2=1			
00001C88				1463	VRR_I	VCVBG, 9, 0	
00001C88		00001C88		1464+	DS	0FD	
00001C88	00001CA4			1465+	USING	*, R5	base for test data and test routine
00001C8C	0021			1466+T33	DC	A(X33)	address of test routine
				1467+	DC	H' 33'	test number

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C8E	00			1468+	DC	XL1' 00'	
00001C8F	09			1469+	DC	HL1' 9'	&MB
00001C90	00			1470+	DC	HL1' 0'	cc
00001C91	07			1471+	DC	HL1' 7'	cc failed mask
00001C92	E5C3E5C2 C7404040			1472+	DC	CL8' VCVBG'	instruction name
00001C9C	00000010			1473+	DC	A(16)	result length
00001CA0	00001CC8			1474+REA33	DC	A(RE33)	result address
				1475+*			INSTRUCTION UNDER TEST ROUTINE
00001CA4				1476+X33	DS	0F	
00001CA4	E310 8EE8 0004		000010E8	1477+	LG	R1, R1FUDGE	pollute R1
00001CAA	E710 5048 0006		00001CD0	1478+	VL	V1, RE33+8	get V1 source
00001CB0	E611 0090 0052			1479+	VCVBG	R1, V1, 9	test instruction
00001CB6	E310 8F20 0024		00001120	1480+	STG	R1, R10UTPUT	save
00001CBC	B98D 0020			1481+	EPSW	R2, R0	exptract psw
00001CC0	5020 8ED8		000010D8	1482+	ST	R2, CCPSW	to save CC
00001CC4	07FB			1483+	BR	R11	return
00001CC8				1484+RE33	DC	0F	
00001CC8				1485+	DROP	R5	
00001CC8	00000000 0000000A			1486	DC	XL08' 0000000000000000A'	R1 result
00001CD0	00000000 00000000			1487	DC	XL16' 0000000000000000000000000000000010C'	V1 source
00001CD8	00000000 0000010C						
				1488			
				1489	VRR_I	VCVBG, 9, 0	
00001CE0				1490+	DS	0FD	
00001CE0		00001CE0		1491+	USING	*, R5	base for test data and test routine
00001CE0	00001CFC			1492+T34	DC	A(X34)	address of test routine
00001CE4	0022			1493+	DC	H' 34'	test number
00001CE6	00			1494+	DC	XL1' 00'	
00001CE7	09			1495+	DC	HL1' 9'	&MB
00001CE8	00			1496+	DC	HL1' 0'	cc
00001CE9	07			1497+	DC	HL1' 7'	cc failed mask
00001CEA	E5C3E5C2 C7404040			1498+	DC	CL8' VCVBG'	instruction name
00001CF4	00000010			1499+	DC	A(16)	result length
00001CF8	00001D20			1500+REA34	DC	A(RE34)	result address
				1501+*			INSTRUCTION UNDER TEST ROUTINE
00001CFC				1502+X34	DS	0F	
00001CFC	E310 8EE8 0004		000010E8	1503+	LG	R1, R1FUDGE	pollute R1
00001D02	E710 5048 0006		00001D28	1504+	VL	V1, RE34+8	get V1 source
00001D08	E611 0090 0052			1505+	VCVBG	R1, V1, 9	test instruction
00001D0E	E310 8F20 0024		00001120	1506+	STG	R1, R10UTPUT	save
00001D14	B98D 0020			1507+	EPSW	R2, R0	exptract psw
00001D18	5020 8ED8		000010D8	1508+	ST	R2, CCPSW	to save CC
00001D1C	07FB			1509+	BR	R11	return
00001D20				1510+RE34	DC	0F	
00001D20				1511+	DROP	R5	
00001D20	00000000 0000000A			1512	DC	XL08' 0000000000000000A'	R1 result
00001D28	00000000 00000000			1513	DC	XL16' 0000000000000000000000000000000010D'	V1 source
00001D30	00000000 0000010D						
				1514			
				1515	VRR_I	VCVBG, 9, 0	
00001D38				1516+	DS	0FD	
00001D38		00001D38		1517+	USING	*, R5	base for test data and test routine
00001D38	00001D54			1518+T35	DC	A(X35)	address of test routine
00001D3C	0023			1519+	DC	H' 35'	test number
00001D3E	00			1520+	DC	XL1' 00'	
00001D3F	09			1521+	DC	HL1' 9'	&MB

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001D40	00			1522+	DC	HL1' 0'	cc
00001D41	07			1523+	DC	HL1' 7'	cc failed mask
00001D42	E5C3E5C2 C7404040			1524+	DC	CL8' VCVBG'	instruction name
00001D4C	00000010			1525+	DC	A(16)	result length
00001D50	00001D78			1526+REA35	DC	A(RE35)	result address
				1527+*			INSTRUCTION UNDER TEST ROUTINE
00001D54				1528+X35	DS	OF	
00001D54	E310 8EE8 0004		000010E8	1529+	LG	R1, R1FUDGE	pollute R1
00001D5A	E710 5048 0006		00001D80	1530+	VL	V1, RE35+8	get V1 source
00001D60	E611 0090 0052			1531+	VCVBG	R1, V1, 9	test instruction
00001D66	E310 8F20 0024		00001120	1532+	STG	R1, R10UTPUT	save
00001D6C	B98D 0020			1533+	EPSW	R2, R0	exptract psw
00001D70	5020 8ED8		000010D8	1534+	ST	R2, CCPSW	to save CC
00001D74	07FB			1535+	BR	R11	return
00001D78				1536+RE35	DC	OF	
00001D78				1537+	DROP	R5	
00001D78	00000000 0008A160			1538	DC	XL08' 0000000000008A160'	R1 result
00001D80	00000000 00000000			1539	DC	XL16' 0000000000000000000000000565600C'	V1 source
00001D88	00000000 0565600C						
				1540			
00001D90				1541	VRR_I	VCVBG, 9, 0	
00001D90		00001D90		1542+	DS	OFD	
00001D90	00001DAC			1543+	USING	*, R5	base for test data and test routine
00001D94	0024			1544+T36	DC	A(X36)	address of test routine
00001D96	00			1545+	DC	H' 36'	test number
00001D96	00			1546+	DC	XL1' 00'	
00001D97	09			1547+	DC	HL1' 9'	&MB
00001D98	00			1548+	DC	HL1' 0'	cc
00001D99	07			1549+	DC	HL1' 7'	cc failed mask
00001D9A	E5C3E5C2 C7404040			1550+	DC	CL8' VCVBG'	instruction name
00001DA4	00000010			1551+	DC	A(16)	result length
00001DA8	00001DD0			1552+REA36	DC	A(RE36)	result address
				1553+*			INSTRUCTION UNDER TEST ROUTINE
00001DAC				1554+X36	DS	OF	
00001DAC	E310 8EE8 0004		000010E8	1555+	LG	R1, R1FUDGE	pollute R1
00001DB2	E710 5048 0006		00001DD8	1556+	VL	V1, RE36+8	get V1 source
00001DB8	E611 0090 0052			1557+	VCVBG	R1, V1, 9	test instruction
00001DBE	E310 8F20 0024		00001120	1558+	STG	R1, R10UTPUT	save
00001DC4	B98D 0020			1559+	EPSW	R2, R0	exptract psw
00001DC8	5020 8ED8		000010D8	1560+	ST	R2, CCPSW	to save CC
00001DCC	07FB			1561+	BR	R11	return
00001DD0				1562+RE36	DC	OF	
00001DD0				1563+	DROP	R5	
00001DD0	00000000 0008A160			1564	DC	XL08' 0000000000008A160'	R1 result
00001DD8	00000000 00000000			1565	DC	XL16' 0000000000000000000000000565600D'	V1 source
00001DE0	00000000 0565600D						
				1566			
00001DE8				1567	VRR_I	VCVBG, 9, 0	INT_MAX
00001DE8		00001DE8		1568+	DS	OFD	
00001DE8	00001E04			1569+	USING	*, R5	base for test data and test routine
00001DEC	0025			1570+T37	DC	A(X37)	address of test routine
00001DEE	00			1571+	DC	H' 37'	test number
00001DEE	00			1572+	DC	XL1' 00'	
00001DEF	09			1573+	DC	HL1' 9'	&MB
00001DF0	00			1574+	DC	HL1' 0'	cc
00001DF1	07			1575+	DC	HL1' 7'	cc failed mask

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001DF2	E5C3E5C2 C7404040			1576+	DC	CL8' VCVBG'	instruction name
00001DFC	00000010			1577+	DC	A(16)	result length
00001E00	00001E28			1578+REA37	DC	A(RE37)	result address
				1579+*			INSTRUCTION UNDER TEST ROUTINE
00001E04				1580+X37	DS	OF	
00001E04	E310 8EE8 0004		000010E8	1581+	LG	R1, R1FUDGE	pollute R1
00001E0A	E710 5048 0006		00001E30	1582+	VL	V1, RE37+8	get V1 source
00001E10	E611 0090 0052			1583+	VCVBG	R1, V1, 9	test instruction
00001E16	E310 8F20 0024		00001120	1584+	STG	R1, R10UTPUT	save
00001E1C	B98D 0020			1585+	EPSW	R2, R0	exptract psw
00001E20	5020 8ED8		000010D8	1586+	ST	R2, CCPSW	to save CC
00001E24	07FB			1587+	BR	R11	return
00001E28				1588+RE37	DC	OF	
00001E28				1589+	DROP	R5	
00001E28	00000000 7FFFFFFF			1590	DC	XL08' 000000007FFFFFFF'	R1 result
00001E30	00000000 00000000			1591	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001E38	00000214 7483647C						
				1592			
00001E40				1593	VRR_I	VCVBG, 9, 0	INT_MIN
00001E40		00001E40		1594+	DS	OFD	
00001E40	00001E5C			1595+	USING	*, R5	base for test data and test routine
00001E44	0026			1596+T38	DC	A(X38)	address of test routine
00001E46	00			1597+	DC	H' 38'	test number
00001E47	09			1598+	DC	XL1' 00'	
00001E48	00			1599+	DC	HL1' 9'	&MB
00001E49	07			1600+	DC	HL1' 0'	cc
00001E4A	E5C3E5C2 C7404040			1601+	DC	HL1' 7'	cc failed mask
00001E54	00000010			1602+	DC	CL8' VCVBG'	instruction name
00001E58	00001E80			1603+	DC	A(16)	result length
				1604+REA38	DC	A(RE38)	result address
				1605+*			INSTRUCTION UNDER TEST ROUTINE
00001E5C				1606+X38	DS	OF	
00001E5C	E310 8EE8 0004		000010E8	1607+	LG	R1, R1FUDGE	pollute R1
00001E62	E710 5048 0006		00001E88	1608+	VL	V1, RE38+8	get V1 source
00001E68	E611 0090 0052			1609+	VCVBG	R1, V1, 9	test instruction
00001E6E	E310 8F20 0024		00001120	1610+	STG	R1, R10UTPUT	save
00001E74	B98D 0020			1611+	EPSW	R2, R0	exptract psw
00001E78	5020 8ED8		000010D8	1612+	ST	R2, CCPSW	to save CC
00001E7C	07FB			1613+	BR	R11	return
00001E80				1614+RE38	DC	OF	
00001E80				1615+	DROP	R5	
00001E80	00000000 80000000			1616	DC	XL08' 0000000080000000'	R1 result
00001E88	00000000 00000000			1617	DC	XL16' 000000000000000000000002147483648D'	V1 source
00001E90	00000214 7483648D						
				1618			
00001E98				1619	VRR_I	VCVBG, 9, 0	UINT_MAX
00001E98		00001E98		1620+	DS	OFD	
00001E98	00001EB4			1621+	USING	*, R5	base for test data and test routine
00001E9C	0027			1622+T39	DC	A(X39)	address of test routine
00001E9E	00			1623+	DC	H' 39'	test number
00001E9F	09			1624+	DC	XL1' 00'	
00001EA0	00			1625+	DC	HL1' 9'	&MB
00001EA1	07			1626+	DC	HL1' 0'	cc
00001EA2	E5C3E5C2 C7404040			1627+	DC	HL1' 7'	cc failed mask
00001EAC	00000010			1628+	DC	CL8' VCVBG'	instruction name
				1629+	DC	A(16)	result length

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001EB0	00001ED8			1630+REA39	DC	A(RE39)	result address
				1631+*			INSTRUCTION UNDER TEST ROUTINE
00001EB4				1632+X39	DS	0F	
00001EB4	E310 8EE8 0004		000010E8	1633+	LG	R1, R1FUDGE	pollute R1
00001EBA	E710 5048 0006		00001EE0	1634+	VL	V1, RE39+8	get V1 source
00001EC0	E611 0090 0052			1635+	VCVBG	R1, V1, 9	test instruction
00001EC6	E310 8F20 0024		00001120	1636+	STG	R1, R10UTPUT	save
00001ECC	B98D 0020			1637+	EPSW	R2, R0	exptract psw
00001ED0	5020 8ED8		000010D8	1638+	ST	R2, CCPSW	to save CC
00001ED4	07FB			1639+	BR	R11	return
00001ED8				1640+RE39	DC	0F	
00001ED8				1641+	DROP	R5	
00001ED8	00000000 FFFFFFFF			1642	DC	XL08' 00000000FFFFFFFF'	R1 result
00001EE0	00000000 00000000			1643	DC	XL16' 0000000000000000000000004294967295C'	V1 source
00001EE8	00000429 4967295C						
				1644			
				1645	VRR_I	VCVBG, 9, 0	UINT_MAX +1
00001EF0				1646+	DS	0FD	
00001EF0		00001EF0		1647+	USING	*, R5	base for test data and test routine
00001EF0	00001F0C			1648+T40	DC	A(X40)	address of test routine
00001EF4	0028			1649+	DC	H' 40'	test number
00001EF6	00			1650+	DC	XL1' 00'	
00001EF7	09			1651+	DC	HL1' 9'	&MB
00001EF8	00			1652+	DC	HL1' 0'	cc
00001EF9	07			1653+	DC	HL1' 7'	cc failed mask
00001EFA	E5C3E5C2 C7404040			1654+	DC	CL8' VCVBG'	instruction name
00001F04	00000010			1655+	DC	A(16)	result length
00001F08	00001F30			1656+REA40	DC	A(RE40)	result address
				1657+*			INSTRUCTION UNDER TEST ROUTINE
00001F0C				1658+X40	DS	0F	
00001F0C	E310 8EE8 0004		000010E8	1659+	LG	R1, R1FUDGE	pollute R1
00001F12	E710 5048 0006		00001F38	1660+	VL	V1, RE40+8	get V1 source
00001F18	E611 0090 0052			1661+	VCVBG	R1, V1, 9	test instruction
00001F1E	E310 8F20 0024		00001120	1662+	STG	R1, R10UTPUT	save
00001F24	B98D 0020			1663+	EPSW	R2, R0	exptract psw
00001F28	5020 8ED8		000010D8	1664+	ST	R2, CCPSW	to save CC
00001F2C	07FB			1665+	BR	R11	return
00001F30				1666+RE40	DC	0F	
00001F30				1667+	DROP	R5	
00001F30	00000001 00000000			1668	DC	XL08' 0000000100000000'	R1 result
00001F38	00000000 00000000			1669	DC	XL16' 0000000000000000000000004294967296C'	V1 source
00001F40	00000429 4967296C						
				1670			
				1671	VRR_I	VCVBG, 9, 0	
00001F48				1672+	DS	0FD	
00001F48		00001F48		1673+	USING	*, R5	base for test data and test routine
00001F48	00001F64			1674+T41	DC	A(X41)	address of test routine
00001F4C	0029			1675+	DC	H' 41'	test number
00001F4E	00			1676+	DC	XL1' 00'	
00001F4F	09			1677+	DC	HL1' 9'	&MB
00001F50	00			1678+	DC	HL1' 0'	cc
00001F51	07			1679+	DC	HL1' 7'	cc failed mask
00001F52	E5C3E5C2 C7404040			1680+	DC	CL8' VCVBG'	instruction name
00001F5C	00000010			1681+	DC	A(16)	result length
00001F60	00001F88			1682+REA41	DC	A(RE41)	result address
				1683+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001F64				1684+X41	DS	OF	
00001F64	E310 8EE8 0004		000010E8	1685+	LG	R1, R1FUDGE	pollute R1
00001F6A	E710 5048 0006		00001F90	1686+	VL	V1, RE41+8	get V1 source
00001F70	E611 0090 0052			1687+	VCVBG	R1, V1, 9	test instruction
00001F76	E310 8F20 0024		00001120	1688+	STG	R1, R10UTPUT	save
00001F7C	B98D 0020			1689+	EPSW	R2, R0	exptract psw
00001F80	5020 8ED8		000010D8	1690+	ST	R2, CCPSW	to save CC
00001F84	07FB			1691+	BR	R11	return
00001F88				1692+RE41	DC	OF	
00001F88				1693+	DROP	R5	
00001F88	00000002 DF8E1660			1694	DC	XL08' 00000002DF8E1660'	R1 result
00001F90	00000000 00000000			1695	DC	XL16' 00000000000000000000000012340565600C'	V1 source
00001F98	00001234 0565600C						
				1696			
				1697	VRR_I	VCVBG, 9, 0	LONG_MAX
00001FA0				1698+	DS	OFD	
00001FA0		00001FA0		1699+	USING	*, R5	base for test data and test routine
00001FA0	00001FBC			1700+T42	DC	A(X42)	address of test routine
00001FA4	002A			1701+	DC	H' 42'	test number
00001FA6	00			1702+	DC	XL1' 00'	
00001FA7	09			1703+	DC	HL1' 9'	&MB
00001FA8	00			1704+	DC	HL1' 0'	cc
00001FA9	07			1705+	DC	HL1' 7'	cc failed mask
00001FAA	E5C3E5C2 C7404040			1706+	DC	CL8' VCVBG'	instruction name
00001FB4	00000010			1707+	DC	A(16)	result length
00001FB8	00001FE0			1708+REA42	DC	A(RE42)	result address
				1709+*			INSTRUCTION UNDER TEST ROUTINE
00001FBC				1710+X42	DS	OF	
00001FBC	E310 8EE8 0004		000010E8	1711+	LG	R1, R1FUDGE	pollute R1
00001FC2	E710 5048 0006		00001FE8	1712+	VL	V1, RE42+8	get V1 source
00001FC8	E611 0090 0052			1713+	VCVBG	R1, V1, 9	test instruction
00001FCE	E310 8F20 0024		00001120	1714+	STG	R1, R10UTPUT	save
00001FD4	B98D 0020			1715+	EPSW	R2, R0	exptract psw
00001FD8	5020 8ED8		000010D8	1716+	ST	R2, CCPSW	to save CC
00001FDC	07FB			1717+	BR	R11	return
00001FE0				1718+RE42	DC	OF	
00001FE0				1719+	DROP	R5	
00001FE0	7FFFFFFF FFFFFFFF			1720	DC	XL08' 7FFFFFFF7FFFFFFF'	R1 result
00001FE8	00000000 00009223			1721	DC	XL16' 0000000000009223372036854775807C'	V1 source
00001FF0	37203685 4775807C						
				1722			
				1723	VRR_I	VCVBG, 9, 3	LONG_MIN
00001FF8				1724+	DS	OFD	
00001FF8		00001FF8		1725+	USING	*, R5	base for test data and test routine
00001FF8	00002014			1726+T43	DC	A(X43)	address of test routine
00001FFC	002B			1727+	DC	H' 43'	test number
00001FFE	00			1728+	DC	XL1' 00'	
00001FFF	09			1729+	DC	HL1' 9'	&MB
00002000	03			1730+	DC	HL1' 3'	cc
00002001	0E			1731+	DC	HL1' 14'	cc failed mask
00002002	E5C3E5C2 C7404040			1732+	DC	CL8' VCVBG'	instruction name
0000200C	00000010			1733+	DC	A(16)	result length
00002010	00002038			1734+REA43	DC	A(RE43)	result address
				1735+*			INSTRUCTION UNDER TEST ROUTINE
00002014				1736+X43	DS	OF	
00002014	E310 8EE8 0004		000010E8	1737+	LG	R1, R1FUDGE	pollute R1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000201A	E710 5048 0006		00002040	1738+	VL	V1, RE43+8	get V1 source
00002020	E611 0090 0052			1739+	VCVBG	R1, V1, 9	test instruction
00002026	E310 8F20 0024		00001120	1740+	STG	R1, R10UTPUT	save
0000202C	B98D 0020			1741+	EPSW	R2, R0	exptract psw
00002030	5020 8ED8		000010D8	1742+	ST	R2, CCPSW	to save CC
00002034	07FB			1743+	BR	R11	return
00002038				1744+RE43	DC	0F	
00002038				1745+	DROP	R5	
00002038	80000000 00000000			1746	DC	XL08' 8000000000000000'	R1 result
00002040	00000000 00009223			1747	DC	XL16' 0000000000009223372036854775808D'	V1 source
00002048	37203685 4775808D						
00002050				1748			
00002050				1749	VRR_I	VCVBG, 11, 0	ULONG_MAX
00002050		00002050		1750+	DS	0FD	
00002050	0000206C			1751+	USING	*, R5	base for test data and test routine
00002054	002C			1752+T44	DC	A(X44)	address of test routine
00002056	00			1753+	DC	H' 44'	test number
00002057	0B			1754+	DC	XL1' 00'	
00002058	00			1755+	DC	HL1' 11'	&MB
00002059	07			1756+	DC	HL1' 0'	cc
0000205A	E5C3E5C2 C7404040			1757+	DC	HL1' 7'	cc failed mask
00002064	00000010			1758+	DC	CL8' VCVBG'	instruction name
00002068	00002090			1759+	DC	A(16)	result length
				1760+REA44	DC	A(RE44)	result address
				1761+*			INSTRUCTION UNDER TEST ROUTINE
0000206C				1762+X44	DS	0F	
0000206C	E310 8EE8 0004		000010E8	1763+	LG	R1, R1FUDGE	pollute R1
00002072	E710 5048 0006		00002098	1764+	VL	V1, RE44+8	get V1 source
00002078	E611 00B0 0052			1765+	VCVBG	R1, V1, 11	test instruction
0000207E	E310 8F20 0024		00001120	1766+	STG	R1, R10UTPUT	save
00002084	B98D 0020			1767+	EPSW	R2, R0	exptract psw
00002088	5020 8ED8		000010D8	1768+	ST	R2, CCPSW	to save CC
0000208C	07FB			1769+	BR	R11	return
00002090				1770+RE44	DC	0F	
00002090				1771+	DROP	R5	
00002090	FFFFFFFF FFFFFFFF			1772	DC	XL08' FFFFFFFFFFFFFFFFFF'	R1 result
00002098	00000000 00018446			1773	DC	XL16' 0000000000018446744073709551615C'	V1 source
000020A0	74407370 9551615C						
000020A8				1774			
000020A8				1775	VRR_I	VCVBG, 11, 3	ULONG_MAX +1
000020A8		000020A8		1776+	DS	0FD	
000020A8	000020C4			1777+	USING	*, R5	base for test data and test routine
000020AC	002D			1778+T45	DC	A(X45)	address of test routine
000020AE	00			1779+	DC	H' 45'	test number
000020AF	0B			1780+	DC	XL1' 00'	
000020B0	03			1781+	DC	HL1' 11'	&MB
000020B1	0E			1782+	DC	HL1' 3'	cc
000020B2	E5C3E5C2 C7404040			1783+	DC	HL1' 14'	cc failed mask
000020B2	E5C3E5C2 C7404040			1784+	DC	CL8' VCVBG'	instruction name
000020BC	00000010			1785+	DC	A(16)	result length
000020C0	000020E8			1786+REA45	DC	A(RE45)	result address
				1787+*			INSTRUCTION UNDER TEST ROUTINE
000020C4				1788+X45	DS	0F	
000020C4	E310 8EE8 0004		000010E8	1789+	LG	R1, R1FUDGE	pollute R1
000020CA	E710 5048 0006		000020F0	1790+	VL	V1, RE45+8	get V1 source
000020D0	E611 00B0 0052			1791+	VCVBG	R1, V1, 11	test instruction

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000020D6	E310 8F20 0024		00001120	1792+	STG	R1, R10OUTPUT	save
000020DC	B98D 0020			1793+	EPSW	R2, R0	exptract psw
000020E0	5020 8ED8		000010D8	1794+	ST	R2, CCPSW	to save CC
000020E4	07FB			1795+	BR	R11	return
000020E8				1796+RE45	DC	OF	
000020E8				1797+	DROP	R5	
000020E8	00000000 00000000			1798	DC	XL08' 00000000000000000'	R1 result
000020F0	00000000 00018446			1799	DC	XL16' 00000000000018446744073709551616C'	V1 source
000020F8	74407370 9551616C						
				1800			
				1801	VRR_I	VCVBG, 11, 3	ULONG_MAX +11
00002100				1802+	DS	OFD	
00002100		00002100		1803+	USING	*, R5	base for test data and test routine
00002100	0000211C			1804+T46	DC	A(X46)	address of test routine
00002104	002E			1805+	DC	H' 46'	test number
00002106	00			1806+	DC	XL1' 00'	
00002107	0B			1807+	DC	HL1' 11'	&MB
00002108	03			1808+	DC	HL1' 3'	cc
00002109	0E			1809+	DC	HL1' 14'	cc failed mask
0000210A	E5C3E5C2 C7404040			1810+	DC	CL8' VCVBG'	instruction name
00002114	00000010			1811+	DC	A(16)	result length
00002118	00002140			1812+REA46	DC	A(RE46)	result address
				1813+*			INSTRUCTION UNDER TEST ROUTINE
0000211C				1814+X46	DS	OF	
0000211C	E310 8EE8 0004		000010E8	1815+	LG	R1, R1FUDGE	pollute R1
00002122	E710 5048 0006		00002148	1816+	VL	V1, RE46+8	get V1 source
00002128	E611 00B0 0052			1817+	VCVBG	R1, V1, 11	test instruction
0000212E	E310 8F20 0024		00001120	1818+	STG	R1, R10OUTPUT	save
00002134	B98D 0020			1819+	EPSW	R2, R0	exptract psw
00002138	5020 8ED8		000010D8	1820+	ST	R2, CCPSW	to save CC
0000213C	07FB			1821+	BR	R11	return
00002140				1822+RE46	DC	OF	
00002140				1823+	DROP	R5	
00002140	00000000 0000000A			1824	DC	XL08' 0000000000000000A'	R1 result
00002148	00000000 00018446			1825	DC	XL16' 00000000000018446744073709551626C'	V1 source
00002150	74407370 9551626C						
				1826			
00002158	00000000			1827	DC	F' 0'	END OF TABLE
0000215C	00000000			1828	DC	F' 0'	
				1829 *			
				1830 *	table of pointers to individual load test		
				1831 *			
00002160				1832 E6TESTS	DS	OF	
				1833	PTTABLE		
00002160				1834+TTABLE	DS	OF	
00002160	00001188			1835+	DC	A(T1)	address of test
00002164	000011E0			1836+	DC	A(T2)	address of test
00002168	00001238			1837+	DC	A(T3)	address of test
0000216C	00001290			1838+	DC	A(T4)	address of test
00002170	000012E8			1839+	DC	A(T5)	address of test
00002174	00001340			1840+	DC	A(T6)	address of test
00002178	00001398			1841+	DC	A(T7)	address of test
0000217C	000013F0			1842+	DC	A(T8)	address of test
00002180	00001448			1843+	DC	A(T9)	address of test
00002184	000014A0			1844+	DC	A(T10)	address of test
00002188	000014F8			1845+	DC	A(T11)	address of test

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1888	*****
				1889	* Register equates
				1890	*****
		00000000	00000001	1892 R0	EQU 0
		00000001	00000001	1893 R1	EQU 1
		00000002	00000001	1894 R2	EQU 2
		00000003	00000001	1895 R3	EQU 3
		00000004	00000001	1896 R4	EQU 4
		00000005	00000001	1897 R5	EQU 5
		00000006	00000001	1898 R6	EQU 6
		00000007	00000001	1899 R7	EQU 7
		00000008	00000001	1900 R8	EQU 8
		00000009	00000001	1901 R9	EQU 9
		0000000A	00000001	1902 R10	EQU 10
		0000000B	00000001	1903 R11	EQU 11
		0000000C	00000001	1904 R12	EQU 12
		0000000D	00000001	1905 R13	EQU 13
		0000000E	00000001	1906 R14	EQU 14
		0000000F	00000001	1907 R15	EQU 15
				1909	*****
				1910	* Register equates
				1911	*****
		00000000	00000001	1913 V0	EQU 0
		00000001	00000001	1914 V1	EQU 1
		00000002	00000001	1915 V2	EQU 2
		00000003	00000001	1916 V3	EQU 3
		00000004	00000001	1917 V4	EQU 4
		00000005	00000001	1918 V5	EQU 5
		00000006	00000001	1919 V6	EQU 6
		00000007	00000001	1920 V7	EQU 7
		00000008	00000001	1921 V8	EQU 8
		00000009	00000001	1922 V9	EQU 9
		0000000A	00000001	1923 V10	EQU 10
		0000000B	00000001	1924 V11	EQU 11
		0000000C	00000001	1925 V12	EQU 12
		0000000D	00000001	1926 V13	EQU 13
		0000000E	00000001	1927 V14	EQU 14
		0000000F	00000001	1928 V15	EQU 15
		00000010	00000001	1929 V16	EQU 16
		00000011	00000001	1930 V17	EQU 17
		00000012	00000001	1931 V18	EQU 18
		00000013	00000001	1932 V19	EQU 19
		00000014	00000001	1933 V20	EQU 20
		00000015	00000001	1934 V21	EQU 21

ASMA Ver. 0.7.0 zvector-e6-11-convertbinary (Zvector E6 VRR-i)						18 Jun 2024 18:57:58 Page 43												
SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES													
BEGIN	I	00000200	2	151	116	147	148	149										
CC	U	00000008	1	512	262													
CCFOUND	X	000010E0	1	484	249	269												
CCMASK	U	00000009	1	513	220													
CCMSG	U	00000322	1	238	232													
CCPRTEXP	C	0000108A	1	464	266													
CCPRTGOT	C	0000109A	1	467	273													
CCPRTLNE	C	00001047	16	459	469	276												
CCPRTLNG	U	00000055	1	469	275													
CCPRTNAME	C	00001074	8	462	259													
CCPRTNUM	C	00001057	3	460	257													
CCPSW	F	000010D8	4	483	246	644	670	696	722	748	774	800	826	852	879	905	931	
					957	983	1009	1035	1061	1087	1117	1143	1169	1195	1221	1247	1273	
					1299	1325	1351	1377	1403	1429	1455	1482	1508	1534	1560	1586	1612	
					1638	1664	1690	1716	1742	1768	1794	1820						
CTLRO	F	00000534	4	405	161	162	163	164										
DECNUM	C	000010C8	16	479	254	256	263	265	270	272	288	290	297	299				
E6TEST	4	00000000	28	507	212													
E6TESTS	F	00002160	4	1832	203													
EDIT	X	0000109C	18	474	255	264	271	289	298									
ENDTEST	U	0000040C	1	319	208													
EOJ	I	00000518	4	395	196	322												
EOJPSW	D	00000508	8	393	395													
FAILCONT	U	000003FC	1	309	279													
FAILED	F	00001000	4	435	311	320												
FAILMSG	U	000003B2	1	286	227													
FAILPSW	D	00000520	8	397	399													
FAILTEST	I	00000530	4	399	323													
FB0001	F	00000288	8	180	184	185	187											
IMAGE	1	00000000	8744	0														
K	U	00000400	1	418	419	420	421											
K64	U	00010000	1	420														
MB	U	00000007	1	511	240	296												
MB	U	00100000	1	421														
MSG	I	00000450	4	355	195	338												
MSGCMD	C	0000049E	9	385	368	369												
MSGMSG	C	000004A7	95	386	362	383	360											
MSGMVC	I	00000498	6	383	366													
MSGOK	I	00000466	2	364	361													
MSGRET	I	00000486	4	379	372	375												
MSGSAVE	F	0000048C	4	382	358	379												
NEXTE6	U	000002DC	1	205	230	314												
OPNAME	C	0000000A	8	515	259	293												
PAGE	U	00001000	1	419														
PRT3	C	000010B2	18	477	255	256	257	264	265	266	271	272	273	289	290	291	298	
PRTLNE	C	00001008	16	444	451	303												
					299	300												
PRTLNG	U	0000003F	1	451	302													
PRTMB	C	00001044	2	449	300													
PRTNAME	C	00001033	8	447	293													
PRTNUM	C	00001018	3	445	291													
R0	U	00000000	1	1892	110	161	164	184	186	187	188	193	210	214	215	275	302	
					310	311	337	339	355	358	360	362	364	379	643	669	695	
					721	747	773	799	825	851	878	904	930	956	982	1008	1034	
					1060	1086	1116	1142	1168	1194	1220	1246	1272	1298	1324	1350	1376	
					1402	1428	1454	1481	1507	1533	1559	1585	1611	1637	1663	1689	1715	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE10	F	000014E0	4	881	871 875
RE11	F	00001538	4	907	897 901
RE12	F	00001590	4	933	923 927
RE13	F	000015E8	4	959	949 953
RE14	F	00001640	4	985	975 979
RE15	F	00001698	4	1011	1001 1005
RE16	F	000016F0	4	1037	1027 1031
RE17	F	00001748	4	1063	1053 1057
RE18	F	000017A0	4	1089	1079 1083
RE19	F	000017F8	4	1119	1109 1113
RE2	F	00001220	4	672	662 666
RE20	F	00001850	4	1145	1135 1139
RE21	F	000018A8	4	1171	1161 1165
RE22	F	00001900	4	1197	1187 1191
RE23	F	00001958	4	1223	1213 1217
RE24	F	000019B0	4	1249	1239 1243
RE25	F	00001A08	4	1275	1265 1269
RE26	F	00001A60	4	1301	1291 1295
RE27	F	00001AB8	4	1327	1317 1321
RE28	F	00001B10	4	1353	1343 1347
RE29	F	00001B68	4	1379	1369 1373
RE3	F	00001278	4	698	688 692
RE30	F	00001BC0	4	1405	1395 1399
RE31	F	00001C18	4	1431	1421 1425
RE32	F	00001C70	4	1457	1447 1451
RE33	F	00001CC8	4	1484	1474 1478
RE34	F	00001D20	4	1510	1500 1504
RE35	F	00001D78	4	1536	1526 1530
RE36	F	00001DD0	4	1562	1552 1556
RE37	F	00001E28	4	1588	1578 1582
RE38	F	00001E80	4	1614	1604 1608
RE39	F	00001ED8	4	1640	1630 1634
RE4	F	000012D0	4	724	714 718
RE40	F	00001F30	4	1666	1656 1660
RE41	F	00001F88	4	1692	1682 1686
RE42	F	00001FE0	4	1718	1708 1712
RE43	F	00002038	4	1744	1734 1738
RE44	F	00002090	4	1770	1760 1764
RE45	F	000020E8	4	1796	1786 1790
RE46	F	00002140	4	1822	1812 1816
RE5	F	00001328	4	750	740 744
RE6	F	00001380	4	776	766 770
RE7	F	000013D8	4	802	792 796
RE8	F	00001430	4	828	818 822
RE9	F	00001488	4	854	844 848
REA1	A	000011A0	4	636	
REA10	A	000014B8	4	871	
REA11	A	00001510	4	897	
REA12	A	00001568	4	923	
REA13	A	000015C0	4	949	
REA14	A	00001618	4	975	
REA15	A	00001670	4	1001	
REA16	A	000016C8	4	1027	
REA17	A	00001720	4	1053	
REA18	A	00001778	4	1079	
REA19	A	000017D0	4	1109	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
REA2	A	000011F8	4	662		
REA20	A	00001828	4	1135		
REA21	A	00001880	4	1161		
REA22	A	000018D8	4	1187		
REA23	A	00001930	4	1213		
REA24	A	00001988	4	1239		
REA25	A	000019E0	4	1265		
REA26	A	00001A38	4	1291		
REA27	A	00001A90	4	1317		
REA28	A	00001AE8	4	1343		
REA29	A	00001B40	4	1369		
REA3	A	00001250	4	688		
REA30	A	00001B98	4	1395		
REA31	A	00001BF0	4	1421		
REA32	A	00001C48	4	1447		
REA33	A	00001CA0	4	1474		
REA34	A	00001CF8	4	1500		
REA35	A	00001D50	4	1526		
REA36	A	00001DA8	4	1552		
REA37	A	00001E00	4	1578		
REA38	A	00001E58	4	1604		
REA39	A	00001EB0	4	1630		
REA4	A	000012A8	4	714		
REA40	A	00001F08	4	1656		
REA41	A	00001F60	4	1682		
REA42	A	00001FB8	4	1708		
REA43	A	00002010	4	1734		
REA44	A	00002068	4	1760		
REA45	A	000020C0	4	1786		
REA46	A	00002118	4	1812		
REA5	A	00001300	4	740		
REA6	A	00001358	4	766		
REA7	A	000013B0	4	792		
REA8	A	00001408	4	818		
REA9	A	00001460	4	844		
READDR	A	00000018	4	518	225	
REG2LOW	U	000000DD	1	425		
REG2PATT	U	AABBCCDD	1	424		
RELEN	A	00000014	4	517		
RPTDWSAV	D	00000440	8	348	337	339
RPTERROR	I	0000041A	4	332	277	304
RPTSAVE	F	00000438	4	345	332	342
RPTSVR5	F	0000043C	4	346	333	341
SKL0001	U	00000054	1	177	193	
SKT0001	C	0000022A	26	174	177	194
SVOLDPSW	U	00000140	0	112		
T1	A	00001188	4	628	1835	
T10	A	000014A0	4	863	1844	
T11	A	000014F8	4	889	1845	
T12	A	00001550	4	915	1846	
T13	A	000015A8	4	941	1847	
T14	A	00001600	4	967	1848	
T15	A	00001658	4	993	1849	
T16	A	000016B0	4	1019	1850	
T17	A	00001708	4	1045	1851	
T18	A	00001760	4	1071	1852	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
V15	U	0000000F	1	1928		
V16	U	00000010	1	1929		
V17	U	00000011	1	1930		
V18	U	00000012	1	1931		
V19	U	00000013	1	1932		
V1FUDGE	X	00001138	16	496		
V1FUDGEb	X	00001148	16	497		
V1INPUT	C	00001158	16	498		
V10OUTPUT	X	00001100	16	492		
V2	U	00000002	1	1915		
V20	U	00000014	1	1933		
V21	U	00000015	1	1934		
V22	U	00000016	1	1935		
V23	U	00000017	1	1936		
V24	U	00000018	1	1937		
V25	U	00000019	1	1938		
V26	U	0000001A	1	1939		
V27	U	0000001B	1	1940		
V28	U	0000001C	1	1941		
V29	U	0000001D	1	1942		
V3	U	00000003	1	1916		
V30	U	0000001E	1	1943		
V31	U	0000001F	1	1944		
V4	U	00000004	1	1917		
V5	U	00000005	1	1918		
V6	U	00000006	1	1919		
V7	U	00000007	1	1920		
V8	U	00000008	1	1921		
V9	U	00000009	1	1922		
X0001	U	000002B0	1	183	171	184
X1	F	000011A4	4	638	628	
X10	F	000014BC	4	873	863	
X11	F	00001514	4	899	889	
X12	F	0000156C	4	925	915	
X13	F	000015C4	4	951	941	
X14	F	0000161C	4	977	967	
X15	F	00001674	4	1003	993	
X16	F	000016CC	4	1029	1019	
X17	F	00001724	4	1055	1045	
X18	F	0000177C	4	1081	1071	
X19	F	000017D4	4	1111	1101	
X2	F	000011FC	4	664	654	
X20	F	0000182C	4	1137	1127	
X21	F	00001884	4	1163	1153	
X22	F	000018DC	4	1189	1179	
X23	F	00001934	4	1215	1205	
X24	F	0000198C	4	1241	1231	
X25	F	000019E4	4	1267	1257	
X26	F	00001A3C	4	1293	1283	
X27	F	00001A94	4	1319	1309	
X28	F	00001AEC	4	1345	1335	
X29	F	00001B44	4	1371	1361	
X3	F	00001254	4	690	680	
X30	F	00001B9C	4	1397	1387	
X31	F	00001BF4	4	1423	1413	
X32	F	00001C4C	4	1449	1439	

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image Region CSECT	IMAGE	8744	0000-2227	0000-2227
		8744	0000-2227	0000-2227
	ZVE6TST	8744	0000-2227	0000-2227

STMT	FILE NAME
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1	/home/tn529/sharedvfp/tests/zvector-e6-11-convertbinary.asm
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**** NO ERRORS FOUND ****